



EN 55022:2010
EN 55024:2010
EN 61000-3-2:2006 + A1:2009 + A2:2009
EN 61000-3-3:2008

TEST REPORT

For

YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD

4th-5th Floor, South Building, NO. 63 WangHai Road, 2nd Software Park, Xiamen, China

Model: SIP-T22P, SIP-T22

Report Type: Amended Report	Product Type: IP PHONE
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DOCUMENT REVISION HISTORY

Revision Number	Report Number	Description of Revision	Date of Issue
0	RSZ09111601-1	Original Report	2010-01-19
1	RSZA11040108-1 RSZA11040108-2	Amended Report	2011-05-12
2	RSZ130619007-01A2	Amended Report	2013-07-11

Note:

This is an amended report application based on RSZA11040108-1 and RSZA11040108-2, the details as below:

- 1) Adding two new adapters: OH-1006B0501200U-VDE and NSA6EE-050120
- 2) Adding standards: EN 61000-3-2:2006 + A1:2009 + A2:2009 and EN 61000-3-3:2008

Based on the above difference, it affects test items “Conducted Disturbance”, “Radiated Disturbance” and adds two test items “Harmonic Current Emissions”, “Voltage Fluctuation and Flicker”, so the related test items were performed, related setup photos and EUT photos were updated, and the other test data and photos were copied from the first amended reports RSZA11040108-1 and RSZA11040108-2 that issued on 2011-05-12.

GENERAL INFORMATION

Product Description for Equipment Under Test (EUT)

The *YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.* 's product, model number: *SIP-T22P* (the "EUT") in this report is an *IP PHONE*, which was measured approximately: 21.0 cm (L) x 19.0 cm (W) x 15.6 cm (H), rated input voltage: DC 5V from adapter. The highest operating frequency of CPU is 125 MHz.

Adapter 1 (original) information:

Model: OH-1048A0501200U1

Input: AC 100-240V, 50/60Hz, 250mA

Output: DC 5V, 1.2A

Adapter 2 (new) information:

Model: OH-1006B0501200U-VDE

Input: AC 100-240V, 50/60Hz, 250mA

Output: DC 5V, 1.2A

Adapter 3 (new) information:

Model: NSA6EE-050120

Input: AC 100-240V, 50/60Hz, 0.2A

Output: DC 5V, 1.2A

Note: The product IP PHONE, model SIP-T22 is electrically identical with the model SIP-T22P which is selected to test, the difference between them is explained in the attached declaration letter.

**All measurement and test data in this report was gathered from production sample serial number: 1306043
(Assigned by BACL, Shenzhen). The EUT supplied by applicable was received on 2013-06-19.*

Objective

This test report is prepared on behalf of *YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.* in accordance with EN 55022: Information technology equipment – Radio disturbance characteristics – Limits and methods of measurement. EN 55024: Information technology equipment- Immunity characteristics – Limits and methods of measurement, EN 61000-3-2, Limits – Limits for harmonic current emissions (equipment input current up to and including 16 A per phase), and also in accordance with EN 61000-3-3, Limits Section 3; Limitation of voltage fluctuations and flicker in low-voltage supply systems for equipment with rated current<16A.

The objective of the manufacturer is to determine compliance with EN 55022, EN 55024, EN 61000-3-2 and EN 61000-3-3.

Related Submittal(s)/Grant(s)

No related submittal(s).

Test Methodology

All measurements contained in this report were conducted with CISPR 16-1-1:2010, specification for radio disturbance and immunity measuring apparatus and methods P1-1: radio disturbance and immunity measuring apparatus measuring apparatus. CISPR 16-1-4:2012, Specification for radio disturbance and immunity measuring apparatus and methods-Part 1-4: Radio disturbance and immunity measuring apparatus -Ancillary equipment -Radiated disturbances. CISPR 16-2-1:2010, specification for radio disturbance and immunity measuring apparatus and methods P2-1: methods of measurement of disturbance and immunity conducted disturbance measurements. CISPR 16-2-3:2010, specification for radio disturbance and immunity measuring apparatus and methods P2-3 methods of measurement of disturbances and immunity radiated disturbance measurements. CISPR 16-4-2:2011, Specification for radio disturbance and immunity measuring apparatus and methods-Part 4-2: Uncertainties, statistics and limit modeling-Uncertainty in EMC measurements

All radiated and conducted emissions measurements were performed at Bay Area Compliance Laboratories Corp. (Shenzhen). The radiated testing was performed at an antenna-to-EUT distance of 3 Meters.

Test Facility

The test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located on the 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China.

Test site at Bay Area Compliance Laboratories Corp. (Shenzhen) has been fully described in reports submitted to the Federal Communication Commission (FCC). The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on December 06, 2010. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-2009.

The Federal Communications Commission has the reports on file and is listed under FCC Registration No.: 382179. The test site has been approved by the FCC for public use and is listed in the FCC Public Access Link (PAL) database.

SYSTEM TEST CONFIGURATION

Justification

The system was configured for testing in a manufacturer testing fashion.

Equipment Modifications

No modification was made to the EUT tested.

Support Equipment List and Details

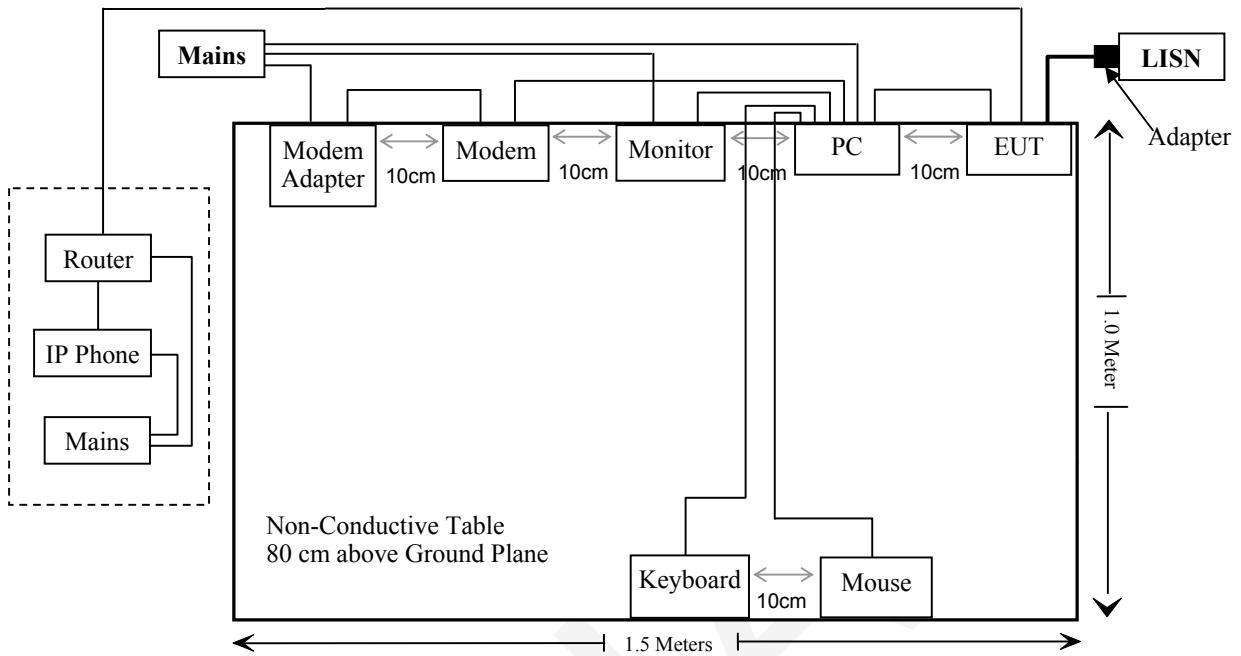
Manufacturer	Description	Model	Serial Number
DELL	PC	127BPX2	N/A
DELL	Monitor	E178WFPC	CN-OWY564-64180-7C4-2SQH
DELL	Mouse	MOC5UO	G1B0096D
DELL	Keyboard	L100	CNORH656658907BL04TY
Sagemcom	Router	N/A	N/A
Yealink	IP phone	T26	N/A
ECOM	Modem	5600pbs	N/A
NETGEAR	Prosafe 8 port 10/100 switch with 4 port POE	FS108P	272-10168-02

External I/O Cable

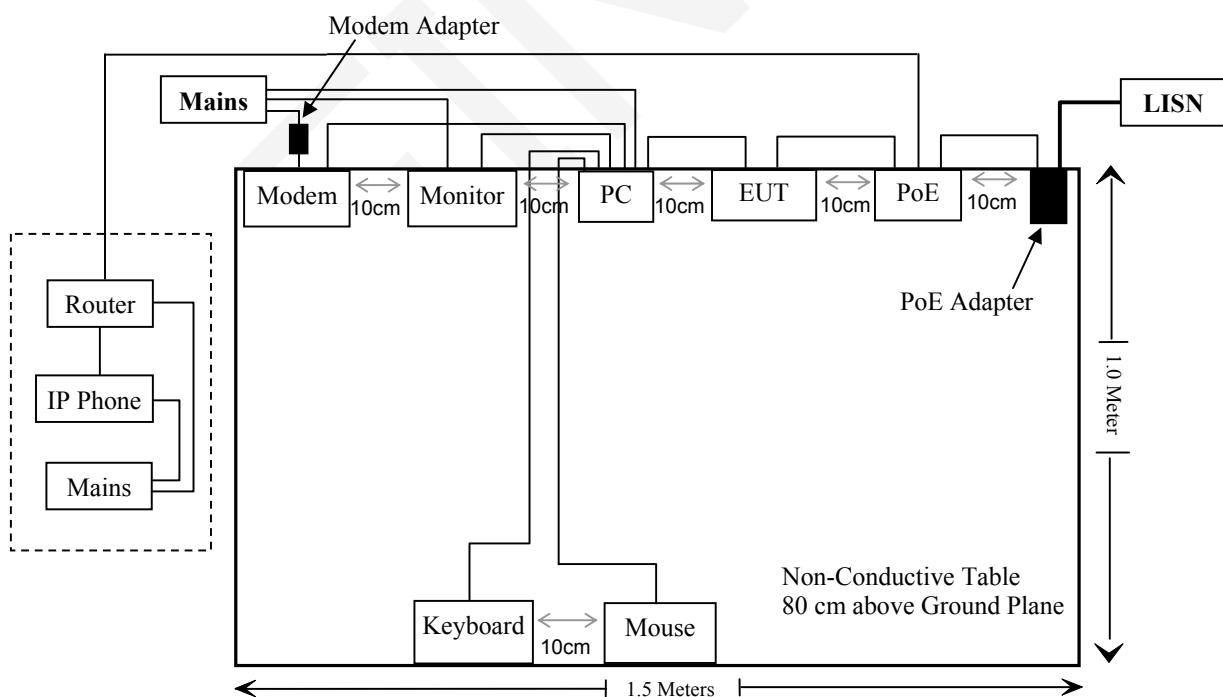
Cable Description	Length (m)	From/Port	To
Shielded Undetachable K/B Cable	1.5	K/B	PC
Shielded Undetachable Mouse Cable	1.5	Mouse	PC
Shielded Undetachable VGA Cable	1.5	Monitor	PC
Unshielded Detachable AC Cable	1.0	Mains	Monitor
Unshielded Detachable RS232 Cable	1.5	Modem	PC
Unshielded Detachable RJ45 Cable	1.5	EUT	PC
Unshielded Detachable DC Cable	1.8	LISN	EUT
Unshielded Detachable AC Cable	1.0	Mains	PC
Unshielded Detachable RJ45 Cable	10	EUT	Router
Unshielded Detachable DC Cable	1.5	Mains	Router
Unshielded Detachable DC Cable	1.8	Mains	IP Phone
Unshielded Detachable RJ45 Cable	1.5	Router	IP Phone
Unshielded Detachable DC Cable	1.5	Modem Adapter	Modem
Unshielded Detachable AC Cable	1.5	Adapter	LISN
Unshielded Detachable RJ45 Cable	1.5	EUT	PoE

Block Diagram of Test Setup

1) Adapter power supply:



2) PoE power supply:



SUMMARY OF TEST REPORT

EN 55022

RULE	DESCRIPTION	RESULTS
§ 5.1	Conducted Disturbance at Mains Terminals	Compliance
§ 5.2	Conducted Disturbance at Telecommunication Port	Compliance
§ 6	Radiated Disturbance	Compliance

EN 55024

RULE	DESCRIPTION	RESULTS
§4.2.1	Electrostatic Discharge IEC 61000-4-2	Compliance
§4.2.2	Electrical Fast Transients IEC 61000-4-4	Compliance
§4.2.3.1	Continuous Radiated Disturbance IEC 61000-4-3	Compliance
§4.2.3.2	Continuous Conducted Disturbance IEC 61000-4-6	Compliance
§4.2.4	Power Frequency Magnetic Fields IEC 61000-4-8	Compliance
§4.2.5	Surges IEC 61000-4-5	Compliance
§4.2.6	Voltage Dips And Interruptions, IEC 61000-4-11	Compliance

EN 61000-3-2

RULE	DESCRIPTION	RESULTS
	Harmonic Current Emissions	Compliance

EN 61000-3-3

RULE	DESCRIPTION	RESULTS
	Voltage Fluctuation and Flicker	Compliance

EN 55022 §5.1 & §5.2-CONDUCTED DISTURBANCE AT MAINS TERMINALS AND TELECOMMUNICATION PORT

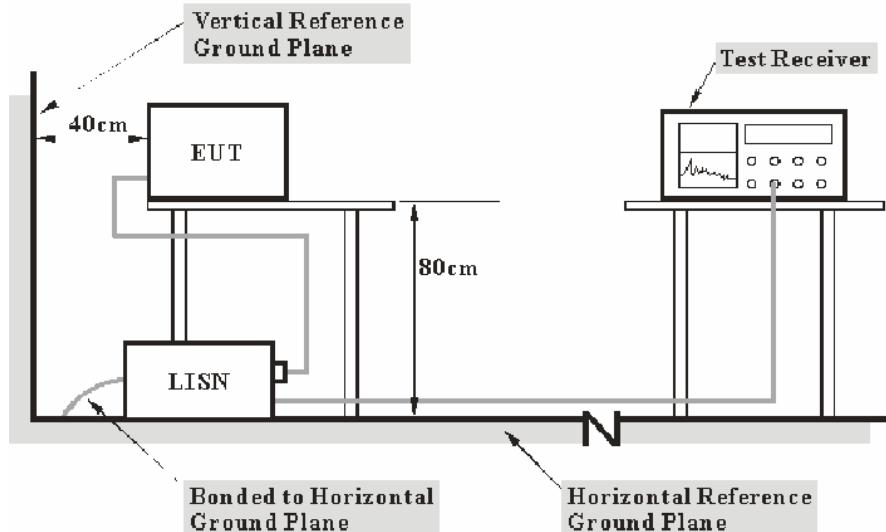
Measurement Uncertainty

Input quantities to be considered for conducted disturbance measurements maybe receiver reading, attenuation of the connection between AMN/ISN and receiver, AMN/ISN voltage division factor, AMN/ISN VDF frequency interpolation and receiver related input quantities, etc.

Based on CISPR 16-4-2:2011, the expended combined standard uncertainty of conducted disturbance test at Bay Area Compliance Laboratories Corp. (Shenzhen) is shown as below. And the uncertainty will not be taken into consideration for the test data recorded in the report

Port	Measurement uncertainty
AC Mains	3.26 dB (k=2, 95% level of confidence)
CAT 3	3.70 dB (k=2, 95% level of confidence)
CAT 5	3.86 dB (k=2, 95% level of confidence)
CAT 6	4.64 dB (k=2, 95% level of confidence)

Test System Setup



- Note: 1. Support units were connected to second LISN.
2. Both of LISNs (AMN) 80 cm from EUT and at the least 80 cm from other units and other metal planes support units.

The setup of EUT is according with CISPR 16-2-1:2010 measurement procedure. The related limit was specified in the EN 55022 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to an AC 230V/50 Hz power source.

EMI Test Receiver Setup

The EMI test receiver was set to investigate the spectrum from 150 kHz to 30 MHz.

During the conducted emission test, the EMI test receiver was set with the following configurations:

Frequency Range	IF B/W
150 kHz – 30 MHz	9 kHz

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Rohde & Schwarz	EMI Test Receiver	ESCS30	100176	2013-06-17	2014-06-17
Rohde & Schwarz	LISN	ESH2-Z5	892107/021	2012-08-22	2013-08-21
Rohde & Schwarz	LISN	ENV216	3560.6650.12-101613-Yb	2013-05-07	2014-05-07
Schwarzbeck	ISN	NTFM 8158	cat 5-8158-0010	2012-11-05	2013-11-05
Rohde & Schwarz	Transient Limiter	ESH3Z2	DE25985	2012-08-09	2013-08-09

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Procedure

During the conducted emission test, the adapter was connected to the outlet of the LISN.

Maximizing procedure was performed on the six (6) highest emissions to ensure EUT compliance using all installation combination.

All data was recorded in the Quasi-peak and average detection mode.

Corrected Factor & Margin Calculation

The Corrected factor is calculated by adding LISN/ISN VDF (Voltage Division Factor) Cable Loss and Transient Limiter Attenuation. The basic equation is as follows:

$$\text{Correction Factor} = \text{LISN VDF} + \text{Cable Loss} + \text{Transient Limiter Attenuation}$$

The “Margin” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7dB means the emission is 7 dB below the limit. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude}$$

Test Results Summary

According to the recorded data in following table, with the worst margin reading of:

1.0 dB at 0.210000 MHz in the **Line** conducted mode (PoE power supply)

Refer to CISPR16-4-2:2011 and CISPR 16-4-1:2009, the measured level is in compliance with the limit if

$$L_m + U_{(Lm)} \leq L_{lim} + U_{cisp}$$

in BACL, $U_{(Lm)}$ is less than U_{cisp} , if L_m is less than L_{lim} , it implies that the EUT complies with the limit.

Test Data

Environmental Conditions

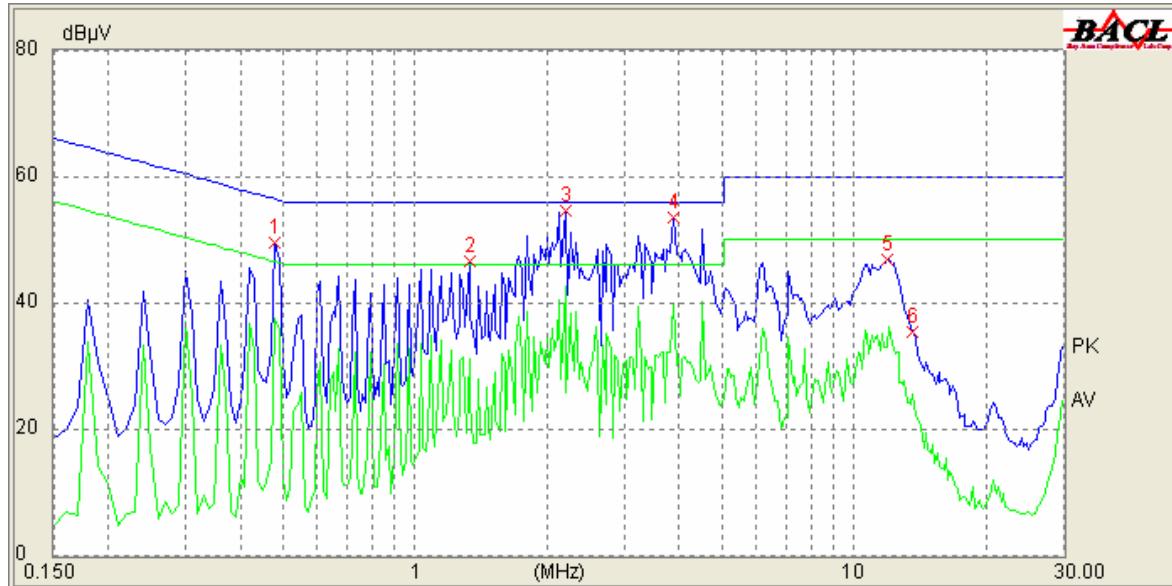
Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Joson Xiao on 2013-07-04.

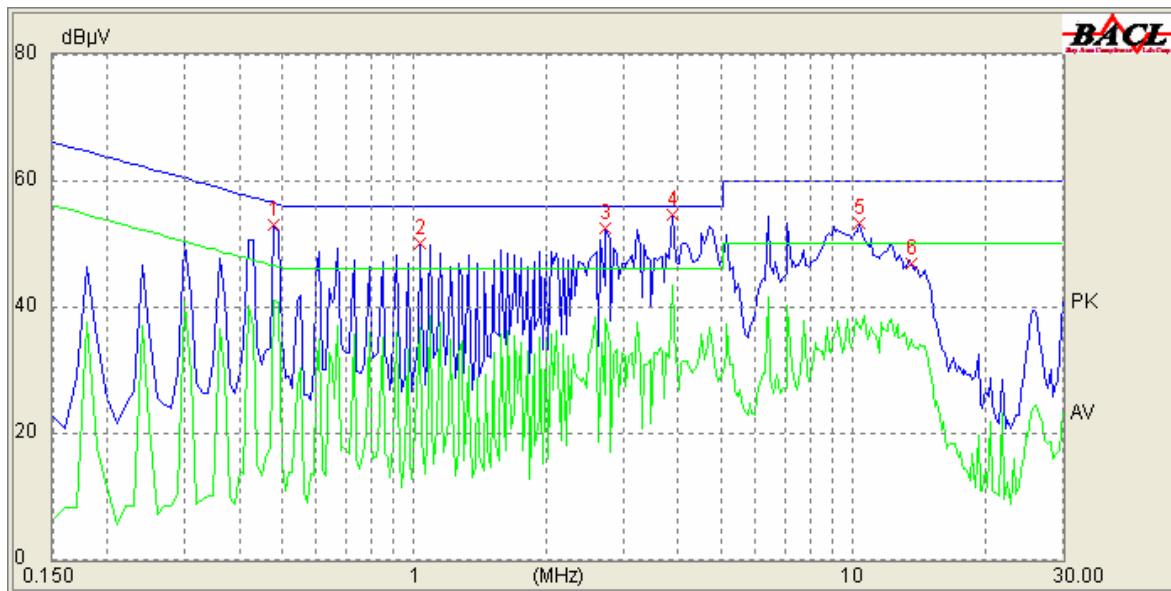
Test Mode: Talking

1) Adapter 1 power supply:

AC 230V/50 Hz, Line:



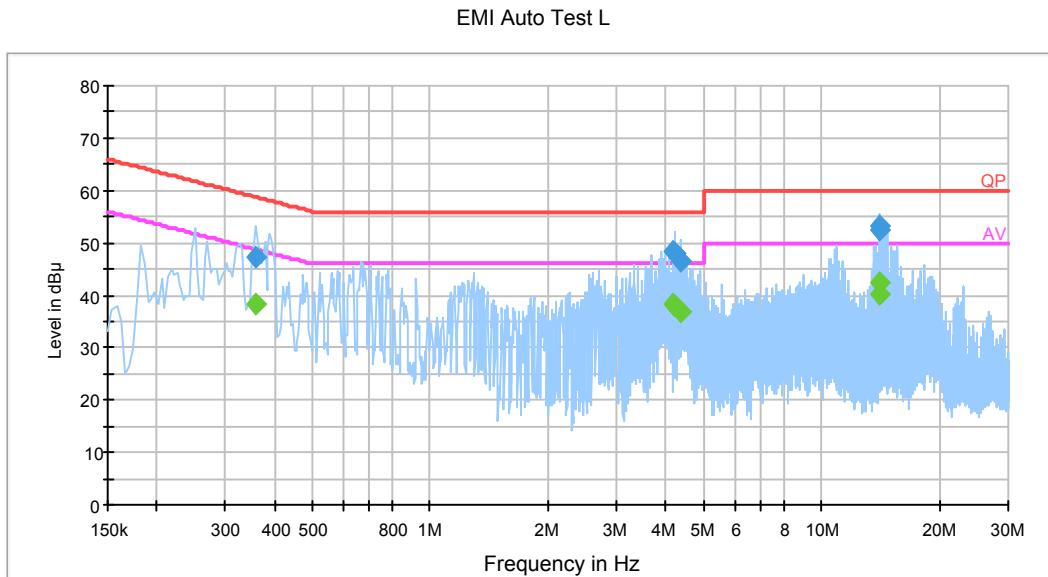
Frequency (MHz)	Correct (dB)	Result (dB μ V)	Detector (PK/Ave./QP)	Limit (dB μ V)	Margin (dB)
2.200	10.10	42.43	Ave.	46.00	3.57
3.870	10.10	39.76	Ave.	46.00	6.24
3.870	10.10	49.03	QP	56.00	6.97
0.480	10.10	37.34	Ave.	46.43	9.09
0.480	10.10	44.29	QP	56.43	12.14
11.970	10.30	45.78	QP	60.00	14.22
1.330	10.10	31.09	Ave.	46.00	14.91
11.970	10.30	32.95	Ave.	50.00	17.05
1.330	10.10	37.62	QP	56.00	18.38
13.590	10.30	36.18	QP	60.00	23.82
13.660	10.30	25.45	Ave.	50.00	24.55
2.200	10.10	30.65	QP	56.00	25.35

AC 230V/50 Hz, Neutral:

Frequency (MHz)	Correct (dB)	Result (dB μ V)	Detector (PK/Ave./QP)	Limit (dB μ V)	Margin (dB)
3.870	10.10	43.25	Ave.	46.00	2.75*
3.870	10.10	50.78	QP	56.00	5.22
0.480	10.10	40.94	Ave.	46.43	5.49
0.480	10.10	48.69	QP	56.43	7.74
2.730	10.10	37.98	Ave.	46.00	8.02
2.730	10.10	47.96	QP	56.00	8.04
1.030	10.10	47.13	QP	56.00	8.87
1.030	10.10	36.80	Ave.	46.00	9.20
10.330	10.30	37.03	Ave.	50.00	12.97
10.330	10.30	45.74	QP	60.00	14.26
13.660	10.30	34.67	Ave.	50.00	15.33
13.660	10.30	43.12	QP	60.00	16.88

2) Adapter 2 power supply:

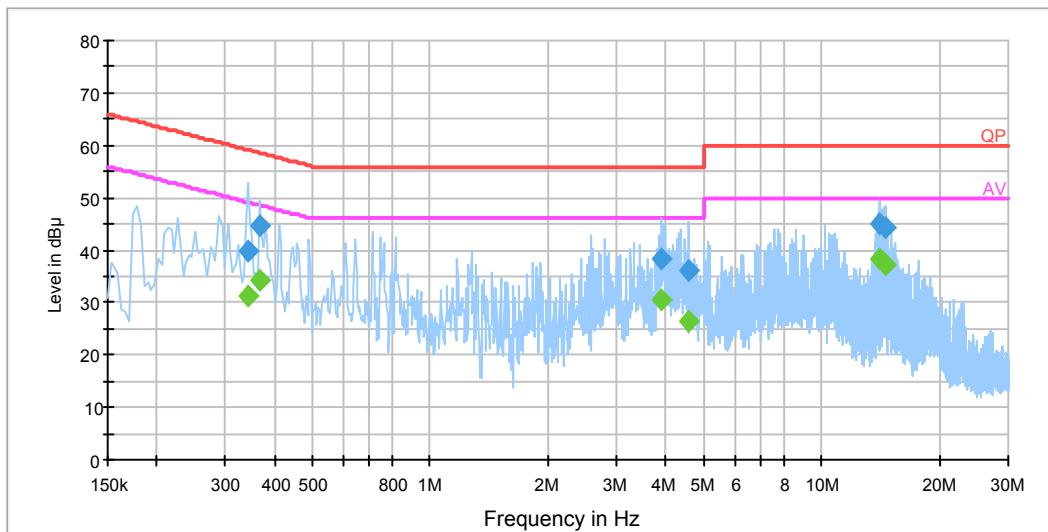
AC 230V/50 Hz, Line:



Frequency (MHz)	Corrected Amplitude (dB μ V)	Correction Factor (dB)	Limit (dB μ V)	Margin (dB)	Detector (PK/Ave./QP)
0.358000	47.2	19.5	58.8	11.6	QP
4.154000	48.2	19.6	56.0	7.8	QP
4.230000	48.1	19.6	56.0	7.9	QP
4.382000	46.3	19.6	56.0	9.7	QP
14.074000	52.4	19.9	60.0	7.6	QP
14.154000	53.0	19.9	60.0	7.0	QP
0.358000	38.4	19.5	48.8	10.4	Ave.
4.154000	38.2	19.6	46.0	7.8	Ave.
4.230000	37.9	19.6	46.0	8.1	Ave.
4.382000	36.9	19.6	46.0	9.1	Ave.
14.074000	40.3	19.9	50.0	9.7	Ave.
14.154000	42.3	19.9	50.0	7.7	Ave.

AC 230V/50 Hz, Neutral:

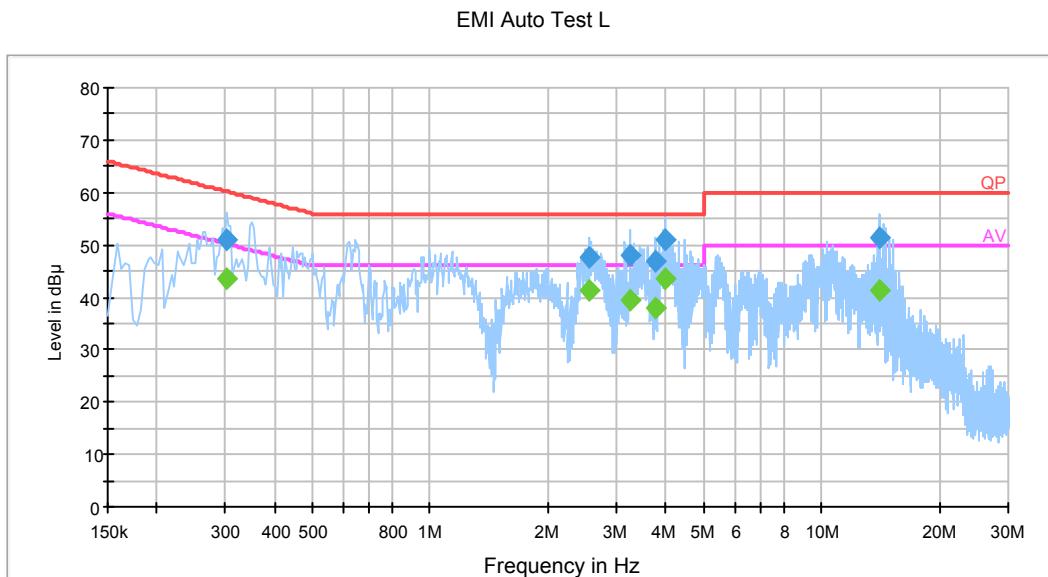
EMI Auto Test N



Frequency (MHz)	Corrected Amplitude (dB μ V)	Correction Factor (dB)	Limit (dB μ V)	Margin (dB)	Detector (PK/Ave./QP)
0.342000	39.8	19.5	59.2	19.4	QP
0.366000	44.8	19.5	58.6	13.8	QP
3.918000	38.2	19.6	56.0	17.8	QP
4.586000	36.2	19.7	56.0	19.8	QP
14.154000	45.2	20.0	60.0	14.8	QP
14.618000	44.3	20.0	60.0	15.7	QP
0.342000	31.2	19.5	49.2	18.0	Ave.
0.366000	34.3	19.5	48.6	14.3	Ave.
3.918000	30.6	19.6	46.0	15.4	Ave.
4.586000	26.5	19.7	46.0	19.5	Ave.
14.154000	38.3	20.0	50.0	11.7	Ave.
14.618000	37.3	20.0	50.0	12.7	Ave.

3) Adapter 3 power supply:

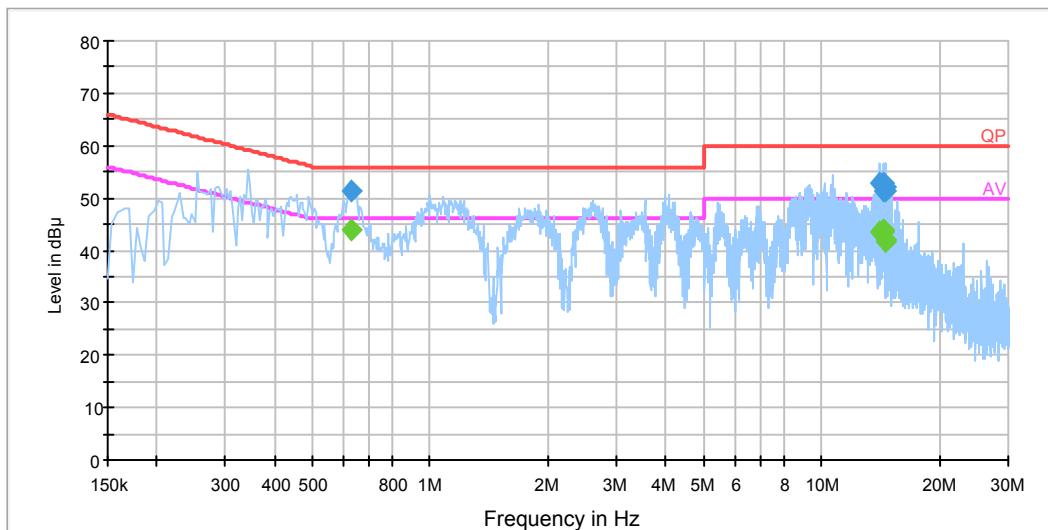
AC 230V/50 Hz, Line:



Frequency (MHz)	Corrected Amplitude (dB μ V)	Correction Factor (dB)	Limit (dB μ V)	Margin (dB)	Detector (PK/Ave./QP)
0.302000	50.9	19.5	60.2	9.3	QP
2.538000	47.8	19.5	56.0	8.2	QP
3.230000	48.0	19.6	56.0	8.0	QP
3.766000	46.7	19.6	56.0	9.3	QP
3.998000	51.0	19.6	56.0	5.0	QP
14.078000	51.4	19.9	60.0	8.6	QP
0.302000	43.4	19.5	50.2	6.8	Ave.
2.538000	41.1	19.5	46.0	4.9	Ave.
3.230000	39.4	19.6	46.0	6.6	Ave.
3.766000	37.9	19.6	46.0	8.1	Ave.
3.998000	43.7	19.6	46.0	2.3*	Ave.
14.078000	41.3	19.9	50.0	8.7	Ave.

AC 230V/50 Hz, Neutral:

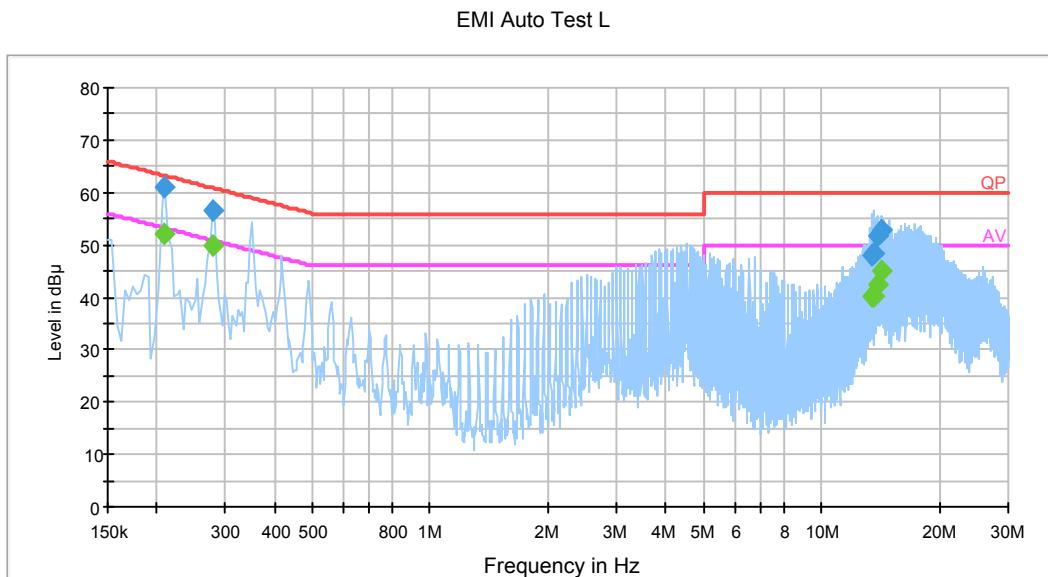
EMI Auto Test N



Frequency (MHz)	Corrected Amplitude (dB μ V)	Correction Factor (dB)	Limit (dB μ V)	Margin (dB)	Detector (PK/Ave./QP)
0.630000	51.4	19.5	56.0	4.6	QP
14.078000	52.8	20.0	60.0	7.2	QP
14.382000	51.5	20.0	60.0	8.5	QP
14.462000	52.9	20.0	60.0	7.1	QP
14.542000	51.5	20.0	60.0	8.5	QP
14.618000	52.2	20.0	60.0	7.8	QP
0.630000	43.9	19.5	46.0	2.1*	Ave.
14.078000	43.5	20.0	50.0	6.5	Ave.
14.382000	43.6	20.0	50.0	6.4	Ave.
14.462000	43.9	20.0	50.0	6.1	Ave.
14.542000	41.8	20.0	50.0	8.2	Ave.
14.618000	42.1	20.0	50.0	7.9	Ave.

4) PoE power supply:

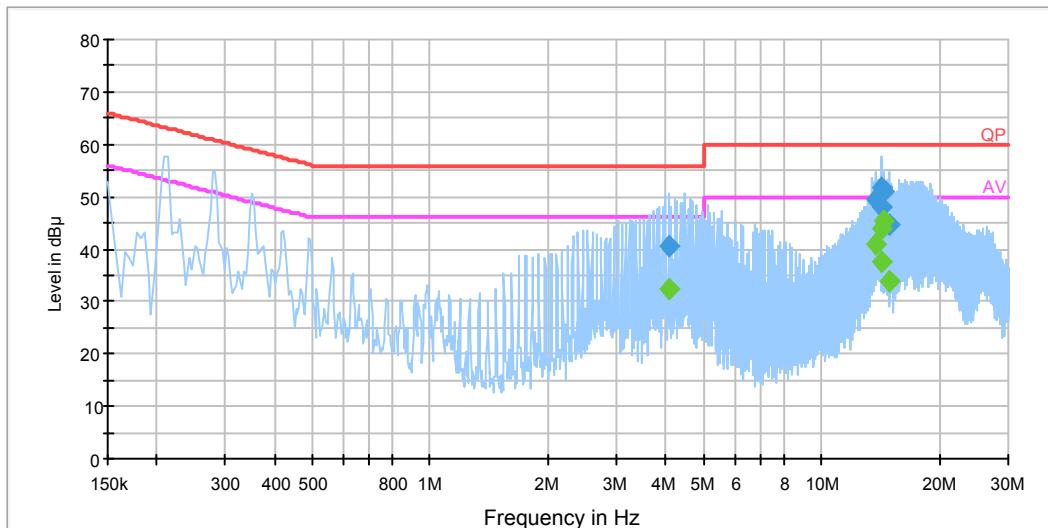
AC 230V/50 Hz, Line:



Frequency (MHz)	Corrected Amplitude (dB μ V)	Correction Factor (dB)	Limit (dB μ V)	Margin (dB)	Detector (PK/Ave./QP)
0.210000	60.9	19.5	63.2	2.3*	QP
0.278000	56.6	19.5	60.9	4.3	QP
13.462000	47.9	19.9	60.0	12.1	QP
13.538000	48.4	19.9	60.0	11.6	QP
13.850000	51.7	19.9	60.0	8.3	QP
14.310000	52.9	19.9	60.0	7.1	QP
0.210000	52.2	19.5	53.2	1.0*	Ave.
0.278000	50.0	19.5	50.9	0.9	Ave.
13.462000	40.1	19.9	50.0	9.9	Ave.
13.538000	40.1	19.9	50.0	9.9	Ave.
13.850000	42.6	19.9	50.0	7.4	Ave.
14.310000	45.0	19.9	50.0	5.0	Ave.

AC 230V/50 Hz, Neutral:

EMI Auto Test N

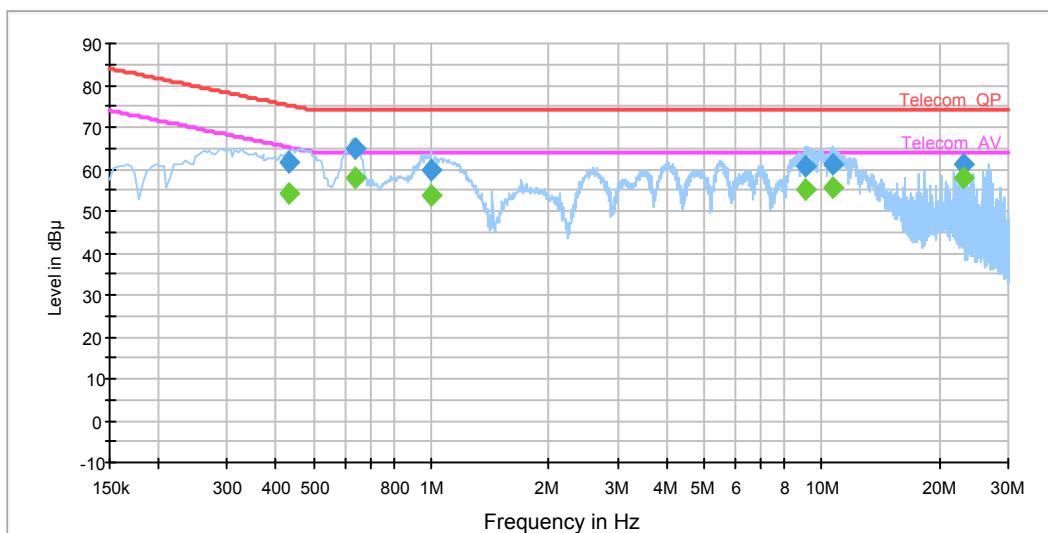


Frequency (MHz)	Corrected Amplitude (dB μ V)	Correction Factor (dB)	Limit (dB μ V)	Margin (dB)	Detector (PK/Ave./QP)
4.074000	40.5	19.7	56.0	15.5	QP
13.766000	49.6	20.0	60.0	10.4	QP
14.238000	48.0	20.0	60.0	12.0	QP
14.306000	51.6	20.0	60.0	8.4	QP
14.466000	51.1	20.0	60.0	8.9	QP
14.930000	44.5	20.0	60.0	15.5	QP
4.074000	32.4	19.7	46.0	13.6	Ave.
13.766000	40.9	20.0	50.0	9.1	Ave.
14.238000	37.7	20.0	50.0	12.3	Ave.
14.306000	43.8	20.0	50.0	6.2	Ave.
14.466000	45.6	20.0	50.0	4.4	Ave.
14.930000	34.0	20.0	50.0	16.0	Ave.

5) Telecommunication Port:

RJ45 Port:

CAT 5 Auto Test



Frequency (MHz)	Corrected Amplitude (dB μ V)	Correction Factor (dB)	Limit (dB μ V)	Margin (dB)	Detector (PK/Ave./QP)
0.430000	61.7	19.7	75.3	13.6	QP
0.638000	64.7	19.6	74.0	9.3	QP
0.998000	59.8	19.6	74.0	14.2	QP
9.098000	60.9	19.4	74.0	13.1	QP
10.610000	61.1	19.4	74.0	12.9	QP
23.130000	60.9	19.7	74.0	13.1	QP
0.430000	54.1	19.7	65.3	11.2	Ave.
0.638000	57.9	19.6	64.0	6.1	Ave.
0.998000	53.7	19.6	64.0	10.3	Ave.
9.098000	55.2	19.4	64.0	8.8	Ave.
10.610000	55.4	19.4	64.0	8.6	Ave.
23.130000	58.0	19.7	64.0	6.0	Ave.

Note:

- 1) Corrected Amplitude = Reading + Correction Factor
- 2) Correction Factor = LISN/ISN VDF (Voltage Division Factor) + Cable Loss + Transient Limiter Attenuation
The corrected factor has been input into the transducer of the test software.
- 3) Margin = Limit – Corrected Amplitude
- 4) *Within measurement uncertainty

EN 55022 §6-RADIATED DISTURBANCE

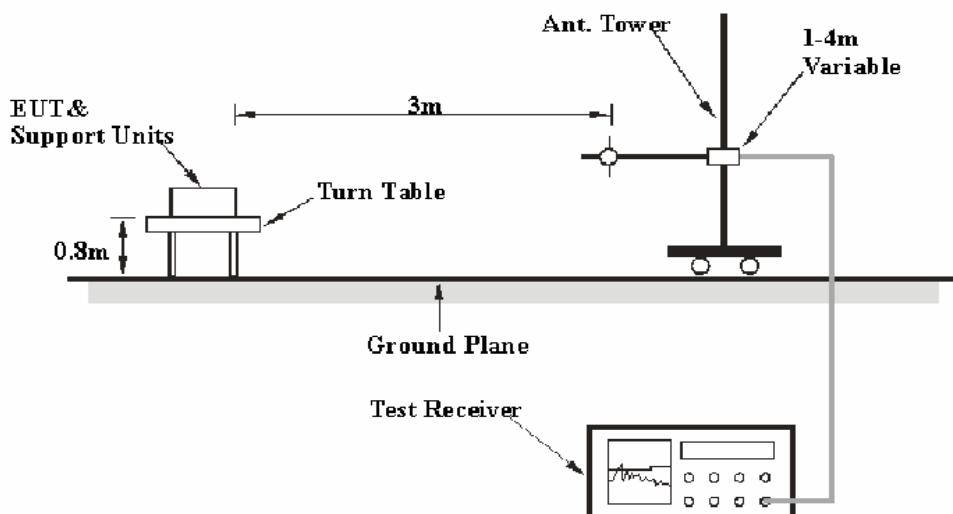
Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, antenna factor calibration, antenna directivity, antenna factor variation with height, antenna phase center variation, antenna factor frequency interpolation, measurement distance variation, site imperfections, mismatch (average), and system repeatability.

Based on CISPR 16-4-2:2011, the expended combined standard uncertainty of radiation emissions at Bay Area Compliance Laboratories Corp. (Shenzhen) is shown in below table. And the uncertainty will not be taken into consideration for the test data recorded in the report

Frequency	Polarity	Measurement uncertainty
30MHz~200MHz	Horizontal	4.62 dB (k=2, 95% level of confidence)
	Vertical	4.54 dB (k=2, 95% level of confidence)
200MHz~1GHz	Horizontal	4.84 dB (k=2, 95% level of confidence)
	Vertical	5.91 dB (k=2, 95% level of confidence)
1 GHz~6 GHz	Horizontal/Vertical	4.68 dB (k=2, 95% level of confidence)
Above 6 GHz	Horizontal/Vertical	4.92 dB (k=2, 95% level of confidence)

Test System Setup



The radiated emission tests were performed in the 3 meters chamber A test site, using the setup accordance with the CISPR16-1-4:2012, CISPR 16-2-3:2010. The limit was specified in EN 55022 Class B.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 230 VAC/50 Hz power source.

EMI Test Receiver Setup

The system was investigated from 30 MHz to 2 GHz.

During the radiated emission test, the EMI test receiver was set with the following configurations:

Frequency Range	RBW	Video B/W	IF B/W	Detector
30 MHz – 1000 MHz	100 kHz	300 kHz	120 kHz	QP
Above 1 GHz	1 MHz	3 MHz	/	PK
	1 MHz	10 Hz	/	Ave.

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
HP	Amplifier	8447E	1937A01046	2012-11-24	2013-11-23
Rohde & Schwarz	EMI Test Receiver	ESCI	101122	2013-05-09	2014-05-09
Sunol Sciences	Broadband Antenna	JB1	A040904-2	2011-11-28	2014-11-27
Mini-Circuits	Amplifier	ZVA-213+	N/A	2012-11-24	2013-11-23
Sunol Sciences	Horn Antenna	DRH-118	A052304	2011-12-01	2014-11-30
Rohde & Schwarz	Signal Analyzer	FSIQ26	8386001028	2012-11-24	2013-11-23
R&S	Auto test Software	EMC32	V6.30	-	-

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Procedure

During the radiated emissions, the adapter was connected to the AC floor outlet.

Maximizing procedure was performed on the highest emissions to ensure that the EUT complied with all installation combinations.

Data was recorded in Quasi-peak detection mode from 30 MHz to 1 GHz, peak and average detection modes for frequencies above 1 GHz.

Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Loss, and subtracting the Amplifier Gain from the Meter Reading. The basic equation is as follows:

$$\text{Corrected Amplitude} = \text{Meter Reading} + \text{Antenna Factor} + \text{Cable Loss} - \text{Amplifier Gain}$$

The “Margin” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7 dB means the emission is 7 dB below the limit for Class B. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude}.$$

Test Results Summary

According to the data in the following table, with the worst margin reading of:

1.9 dB at 106.711200 MHz in the **Vertical** polarization (adapter 2 power supply)

Refer to CISPR16-4-2:2011 and CISPR 16-4-1:2009, the measured level is in compliance with the limit if

$$L_m + U_{(Lm)} \leq L_{\lim} + U_{\text{cisp}}$$

in BACL, $U_{(Lm)}$ is less than U_{cisp} , if L_m is less than L_{\lim} , it implies that the EUT complies with the limit.

Test Data

Environmental Conditions

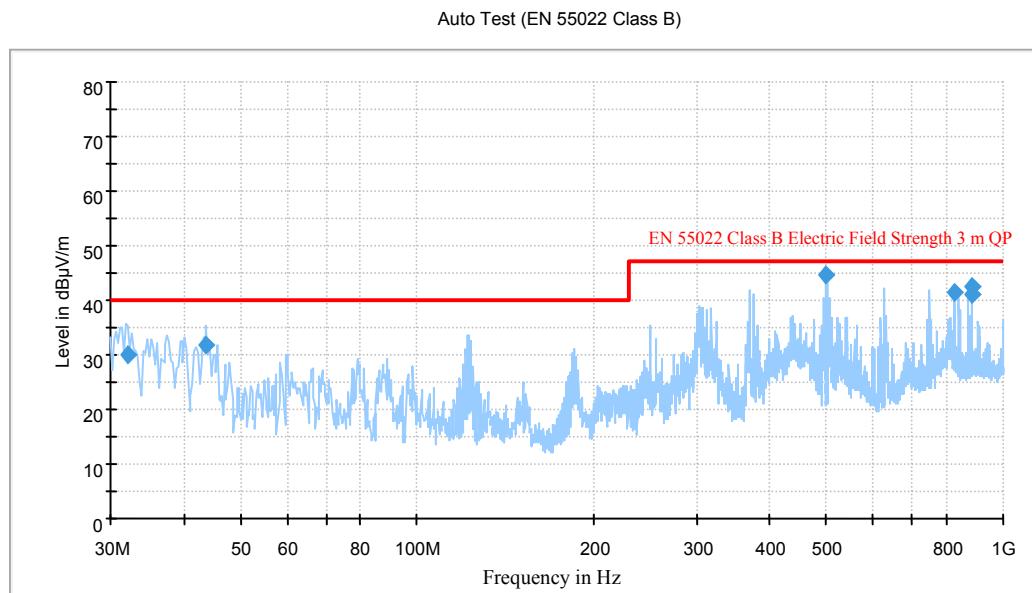
Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Joson Xiao on 2013-07-04.

Test Mode: Talking

1) Adapter 1 power supply:

Below 1 GHz:



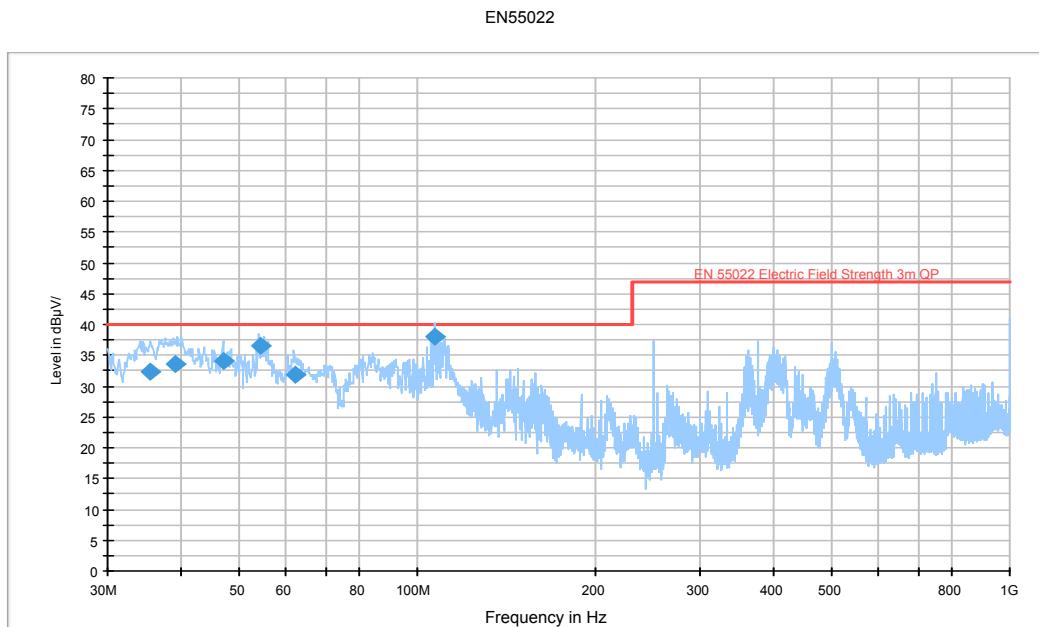
Frequency (MHz)	Corrected Amplitude (dB μ V/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dB μ V/m)	Margin (dB)
499.987750	44.8	203.0	H	158.0	-10.3	47.0	2.2*
884.400500	42.3	331.0	H	348.0	-0.4	47.0	4.7
827.694500	41.5	205.0	V	89.0	-1.4	47.0	5.5
886.186250	41.2	305.0	H	307.0	-0.3	47.0	5.8
43.796750	31.8	100.0	V	271.0	-15.6	40.0	8.2
32.084250	30.0	101.0	V	166.0	-7.6	40.0	10.0

Above 1 GHz:

Frequency (MHz)	Meter Reading (dB μ V)	Detector (PK/QP/Ave.)	Direction (Degree)	Height (m)	Polar H / V	Antenna Factor (dB)	Cable Loss (dB)	Amplifier (dB)	EN 55022		
									Limit (dB μ V/m)	Margin (dB)	
1898	37.20	Ave.	0	1.0	V	29.8	6.32	34.0	39.32	50	10.68
1988	37.10	Ave.	0	1.0	V	29.8	6.32	34.0	39.22	50	10.78
1863	36.90	Ave.	0	1.2	H	29.7	6.32	34.0	38.92	50	11.08
1988	36.70	Ave.	0	1.0	H	29.7	6.32	34.0	38.72	50	11.28
1789	37.20	Ave.	0	1.0	V	28.8	5.99	34.2	37.79	50	12.21
1782	36.30	Ave.	0	1.0	H	28.3	5.99	34.2	36.39	50	13.61
1433	37.30	Ave.	0	1.0	V	27.8	5.62	34.4	36.32	50	13.68
1451	37.30	Ave.	0	1.0	V	27.8	5.62	34.4	36.32	50	13.68
1422	37.20	Ave.	0	1.0	H	27.5	5.62	34.4	35.92	50	14.08
1449	37.20	Ave.	0	1.0	H	27.5	5.62	34.4	35.92	50	14.08
1960	32.60	Ave.	0	1.0	H	29.7	6.32	34.0	34.62	50	15.38
1955	32.40	Ave.	0	1.0	V	29.8	6.32	34.0	34.52	50	15.48
1898	47.05	PK	0	1.0	V	29.8	6.32	34.0	49.17	70	20.83
1988	46.98	PK	0	1.0	V	29.8	6.32	34.0	49.10	70	20.90
1863	46.96	PK	0	1.2	H	29.7	6.32	34.0	48.98	70	21.02
1988	46.66	PK	0	1.0	H	29.7	6.32	34.0	48.68	70	21.32
1955	45.66	PK	0	1.0	V	29.8	6.32	34.0	47.78	70	22.22
1789	47.10	PK	0	1.0	V	28.8	5.99	34.2	47.69	70	22.31
1960	45.62	PK	0	1.0	H	29.7	6.32	34.0	47.64	70	22.36
1782	46.75	PK	0	1.0	H	28.3	5.99	34.2	46.84	70	23.16
1433	47.12	PK	0	1.0	V	27.8	5.62	34.4	46.14	70	23.86
1451	47.11	PK	0	1.0	V	27.8	5.62	34.4	46.13	70	23.87
1449	46.96	PK	0	1.0	H	27.5	5.62	34.4	45.68	70	24.32
1422	46.45	PK	0	1.0	H	27.5	5.62	34.4	45.17	70	24.83

2) Adapter 2 power supply:

Below 1 GHz:



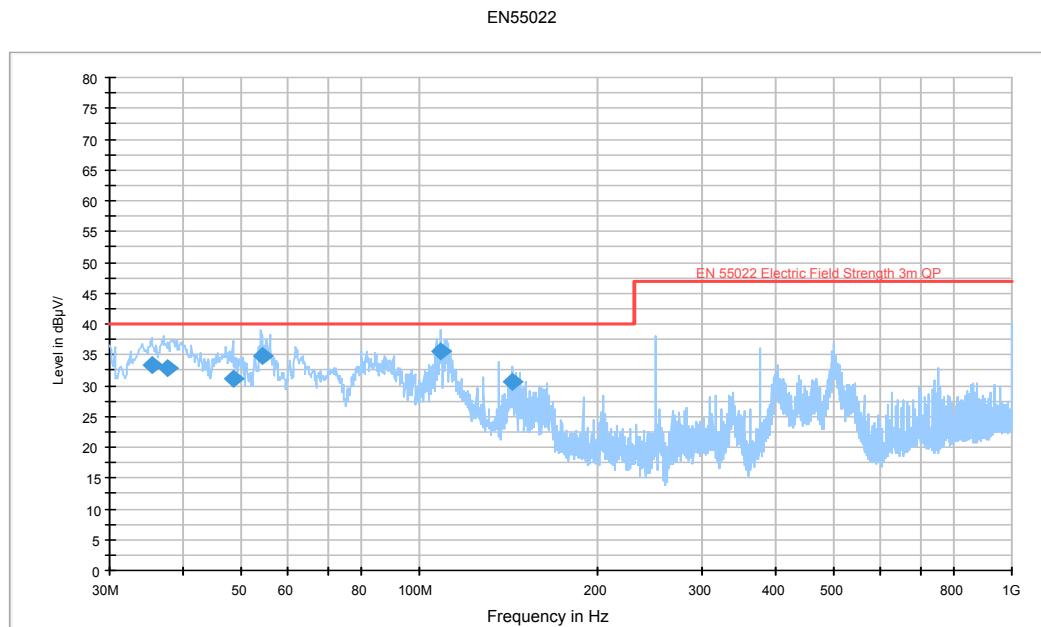
Frequency (MHz)	Corrected Amplitude (dB μ V/m)	Antenna height (cm)	Antenna Polarity	Turntable position (degree)	Correction Factor (dB/m)	Limit (dB μ V/m)	Margin (dB)
35.323500	32.3	125.0	V	107.0	-11.0	40.0	7.7
38.997450	33.7	100.0	V	136.0	-13.6	40.0	6.3
47.002150	34.0	98.0	V	0.0	-18.8	40.0	6.0
54.167300	36.6	98.0	V	89.0	-20.8	40.0	3.4*
62.061000	31.8	98.0	V	190.0	-20.7	40.0	8.2
106.711200	38.1	99.0	V	183.0	-15.6	40.0	1.9*

Above 1 GHz:

Frequency (MHz)	Receiver		Turntable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dB μ V/m)	EN 55022	
	Reading (dB μ V)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dB μ V/m)	Margin (dB)
1198.3	54.65	PK	98	1.3	H	0.13	54.78	70	15.22
1198.3	41.52	Ave.	98	1.3	H	0.13	41.65	50	8.35
1496.9	46.82	PK	239	1.3	V	1.15	47.97	70	22.03
1496.9	39.50	Ave.	239	1.3	V	1.15	40.65	50	9.35
1669.3	48.93	PK	347	1.3	H	2.24	51.17	70	18.83
1669.3	35.75	Ave.	347	1.3	H	2.24	37.99	50	14.01

3) Adapter 3 power supply:

Below 1 GHz:



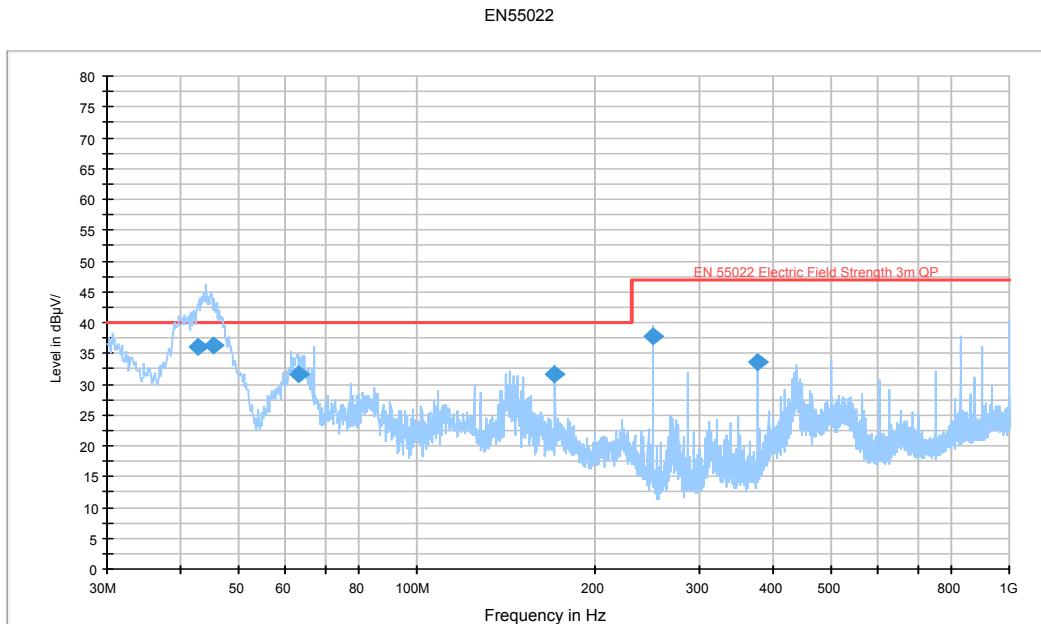
Frequency (MHz)	Corrected Amplitude (dB μ V/m)	Antenna height (cm)	Antenna Polarity	Turtable position (degree)	Correction Factor (dB/m)	Limit (dB μ V/m)	Margin (dB)
35.324650	33.4	98.0	V	95.0	-11.0	40.0	6.6
37.504400	32.8	98.0	V	175.0	-12.6	40.0	7.2
48.491500	31.1	106.0	V	337.0	-19.5	40.0	8.9
54.163400	34.9	111.0	V	119.0	-20.8	40.0	5.1
108.833350	35.5	98.0	V	147.0	-15.2	40.0	4.5*
143.311950	30.6	209.0	H	135.0	-14.5	40.0	9.4

Above 1 GHz:

Frequency (MHz)	Receiver		Turtable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dB μ V/m)	EN 55022	
	Reading (dB μ V)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dB μ V/m)	Margin (dB)
1503.0	57.23	PK	130	1.3	V	1.15	58.38	70	11.62
1503.0	38.34	Ave.	130	1.3	V	1.15	39.49	50	10.51
1537.0	63.39	PK	275	1.5	V	1.15	64.54	70	5.46
1537.0	40.80	Ave.	275	1.5	V	1.15	41.95	50	8.05
1599.1	52.01	PK	19	1.5	V	1.70	53.71	70	16.29
1599.1	33.03	Ave.	19	1.5	V	1.70	34.73	50	15.27

4) PoE power supply:

Below 1 GHz:



Frequency (MHz)	Corrected Amplitude (dB μ V/m)	Antenna height (cm)	Antenna Polarity	Turtable position (degree)	Correction Factor (dB/m)	Limit (dB μ V/m)	Margin (dB)
42.827500	36.1	100.0	V	162.0	-16.4	40.0	3.9*
45.520000	36.2	127.0	H	174.0	-17.9	40.0	3.8*
62.980000	31.5	166.0	H	169.0	-20.8	40.0	8.5
171.256250	31.5	145.0	H	182.0	-15.7	40.0	8.5
249.947500	37.9	100.0	V	155.0	-15.8	47.0	9.1
374.956250	33.6	107.0	V	179.0	-12.9	47.0	13.4

Above 1 GHz:

Frequency (MHz)	Receiver		Turtable Degree	Rx Antenna		Correction Factor (dB/m)	Corrected Amplitude (dB μ V/m)	EN 55022	
	Reading (dB μ V)	Detector (PK/QP/Ave.)		Height (m)	Polar (H/V)			Limit (dB μ V/m)	Margin (dB)
1194.3	44.42	PK	275	1.3	H	0.13	44.55	70	25.45
1194.3	35.75	Ave.	275	1.3	H	0.13	35.88	50	14.12
1501.0	47.75	PK	80	1.2	V	1.15	48.90	70	21.10
1501.0	40.12	Ave.	80	1.2	V	1.15	41.27	50	8.73
1645.2	45.94	PK	189	1.3	V	1.77	47.71	70	22.29
1645.2	38.82	Ave.	189	1.3	V	1.77	40.59	50	9.41

Note: *within measurement uncertainty.

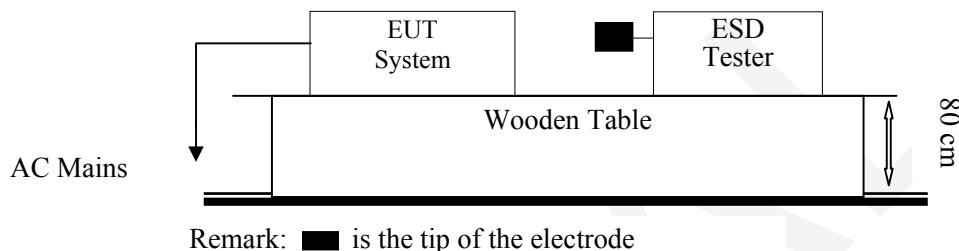
EN 55024 §4.2.1-ELECTROSTATIC DISCHARGES (IEC 61000-4-2)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	ESD Tester	Dito	302105	2009-09-27	2010-09-26

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup



IEC 61000-4-2 specifies that a tabletop EUT shall be placed on a non-conducting table which is 80 centimeters above a ground reference plane and that floor mounted equipment shall be placed on a insulating support approximately 10 centimeters above a ground plane. During the tests, the EUT is positioned over a ground reference plane in conformance with this requirement.

For tabletop equipment, a 1.5 by 1.0-meter metal sheet (HCP) is placed on the table and connected to the ground plane via a metal strap with two 470 k Ohms resistors in series. The EUT and attached cables are isolated from this metal sheet by 0.5-millimeter thick insulating material. A Vertical Coupling Plane (VCP) grounded on the ground plane through the same configuration as in the HCP is used.

Test Standard

EN 55024:2010 (IEC 61000-4-2:2008)
 Test level 3 for Air Discharge at ± 8 kV
 Test level 2 for Contact Discharge at ± 4 kV

Test Level

Level	Test Voltage Contact Discharge (\pm kV)	Test Voltage Air Discharge (\pm kV)
1.	2	2
2.	4	4
3.	6	8
4.	8	15
X.	Special	Special

Performance criterion: B

Test Procedure

Air Discharge:

This test is done on a non-conductive surface. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

Contact Discharge:

All the procedure shall be same as Section 8.3.1 of IEC 61000-4-2, except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

Indirect discharge for horizontal coupling plane

At least 20 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1 m from the EUT and with the discharge electrode touching the coupling plane.

Indirect discharge for vertical coupling plane

At least 20 single discharges shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m × 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jack Wang on 2010-01-14.

Test Mode: Talking

Table 1: Electrostatic Discharge Immunity (Air Discharge)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-8 kV	+8 kV	-15 kV	+15 kV
Surface (8 points)	A	A	A	A	A	A	/	/
Slots (8 points)	A	A	A	A	A	A	/	/
Buttons (26 points)	A	A	A	A	A	A	/	/
LCD (4 points)	A	A	A	A	A	A	/	/
Ports (4 points)	A	A	A	A	A	A	/	/

Table 2: Electrostatic Discharge Immunity (Direct Contact)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Screws (4 points)	A	A	A	A	/	/	/	/

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)

IEC 61000-4-2 Test Points Location	Test Levels							
	-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV
Front Side	A	A	A	A	/	/	/	/
Back Side	A	A	A	A	/	/	/	/
Left Side	A	A	A	A	/	/	/	/
Right Side	A	A	A	A	/	/	/	/

Air Discharge



Indirect Contact



Test Setup Photos

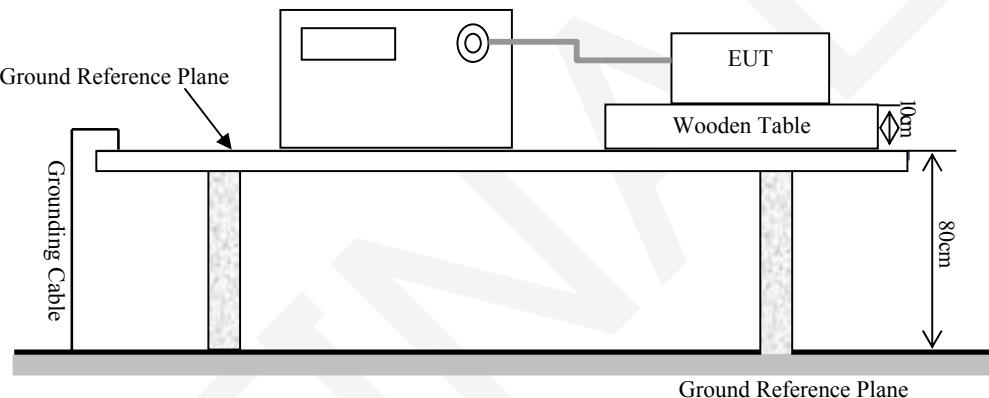
EN 55024 §4.2.2-ELECTRICAL FAST TRANSIENTS (IEC 61000-4-4)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Simulator	UCS 500 N5	V0939105173	2009-10-20	2010-10-20
EM Test	Auto-transformer	MV2616	0403-16	2009-03-25	2010-03-25
EM Test	CNV 504N	CNV 504N	V0939105174	2009-04-28	2010-04-27

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup



Test Standard

EN 55024:2010 (IEC 61000-4-4:2004)

AC mains: Test level 2 at 1 kV

Signal port: Test level 2 at 0.5 kV

Test Level

Open Circuit Output Test Voltage ±10%		
Level	On Power Supply Lines	On I/O (Input/Output) Signal data and control lines
1	0.5 kV	0.25 kV
2	1 kV	0.5 kV
3	2 kV	1 kV
4	4 kV	2 kV
X	Special	Special

Performance Criterion: B

Test Procedure

The EUT was arranged for Power Line Coupling and for I/O Line Coupling through a capacitive clamp, where applicable. (Note: The I/O coupling test using a capacitive clamp is performed on the I/O interface cables that are longer in length than 3 meters.) A metal ground plane 2.4 meter by 2.0 meter was placed between the floor and the table and is connected to the earth by a 2.0 meter ground rod. The ground rod is connected to the test facility's electrical earth.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jack Wang on 2010-01-02.

Test Mode: Talking

IEC 61000-4-4 Test Points	Test Levels (kV)							
	+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
AC mains power input ports	L1	A	A	A	A	/	/	/
	L2	A	A	A	A	/	/	/
	Earth	/	/	/	/	/	/	/
	L1+L2	A	A	A	A	/	/	/
	L1 + Earth	/	/	/	/	/	/	/
	L2 + Earth	/	/	/	/	/	/	/
	L1+L2+Earth	/	/	/	/	/	/	/
Signal ports	RJ45	A	A	/	/	/	/	/

AC Port:



RJ45 Port:



Test Setup Photo

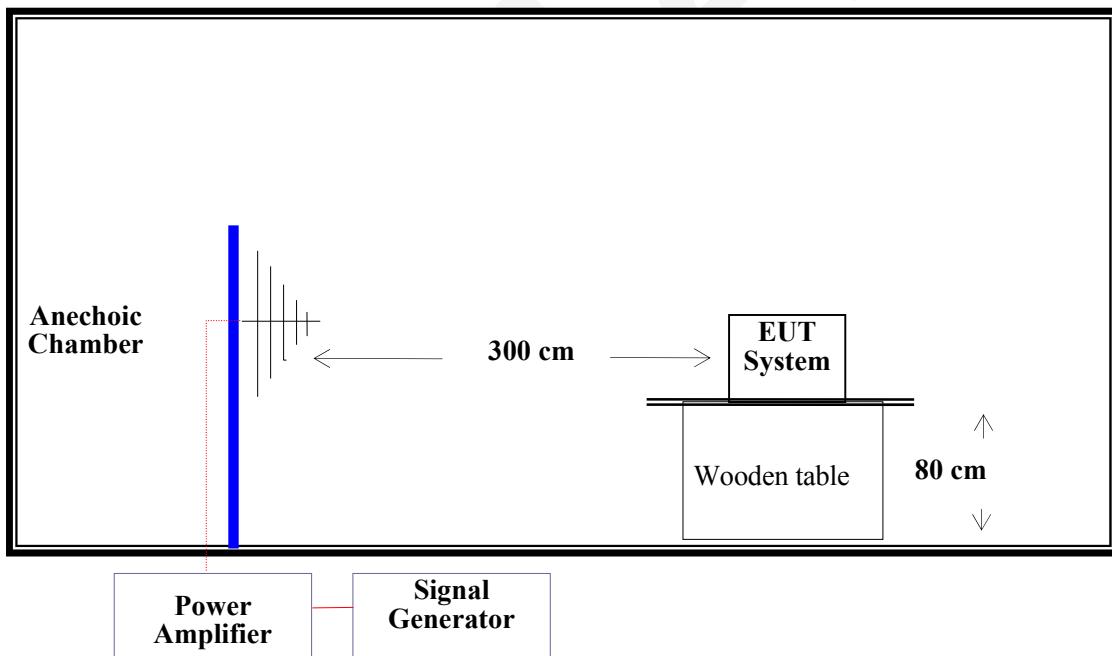
EN 55024 §4.2.3.1-CONTINUOUS RADIATED DISTURBANCES (IEC 61000-4-3)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Amplifier Research	Amplifier Input/Output	200W1000/M2	15893	2009-01-14	2010-01-14
Amplifier Research	Field Meter	FM5004	302149	2009-11-10	2010-11-09
Amplifier Research	Sensor	FP5000	301825	2009-02-22	2010-02-22
HP	Signal Generator	8648C	3426A01345	2009-04-28	2010-04-28
Amplifier Research	Biconilog Antenna	JB1	AT1080	N/A	N/A

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup



Test Standard

EN 55024:2010 (IEC 61000-4-3: 2006 + A1:2007 + A2:2010)
Test level 2 at 3V / m

Test Level

Level	Field Strength V/m
1.	1
2.	3
3.	10
X.	Special

Performance Criterion: A

Test Procedure

The EUT and its simulators are placed on a turn table which is 0.8 meter above the ground. The EUT is set 3 meters away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarizations of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually.

In order to judge the EUT performance, a CCD camera is used to monitor the EUT.
All the scanning conditions are as follows:

Condition of Test	Remarks
1. Field Strength	3 V/m (Test level 2)
2. Radiated Signal	AM 80%, 1 kHz Modulation
3. Scanning Frequency	80 – 1000 MHz
4. Sweeping time of radiated	0.0015decade/s
5. Dwell Time	1Sec.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jack Wang on 2010-01-12.

Test Mode: Talking

Frequency Range (MHz)	Front Side (3 V/m)		Rear Side (3 V/m)		Left Side (3 V/m)		Right Side (3 V/m)	
	VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	A	A	A	A	A	A	A	A



Test Setup Photo

EN 55024 §4.2.3.2-CONTINUOUS CONDUCTED DISTURBANCES (IEC 61000-4-6)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	C/S Tester	CWS500	303277	2009-10-16	2010-10-16
EM Test	Attenuator	6dB	303282	2009-11-15	2010-11-15
EM Test	CDN	T2	1101-07	2009-04-28	2010-04-27
FCC	Bulk current Injection probe	F-120-9A	303284	2009-03-26	2010-03-26
Krohn-hite	Dual channel filter	3940	003096	N/A	N/A
HP	RF Communication Test Set	HP8920A	3438A05201	2009-04-28	2010-04-27
Brüel & Kjær	Ear Simulator	4185	2190351	N/A	N/A

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Setup



Test Standard

EN 55024:2010 (IEC 61000-4-6:2008)
Test level 2 at 3 V (r.m.s.), 0.15 MHz ~ 80 MHz,

Test Level

Level	Voltage Level (r.m.s.) (V)
1	1
2	3
3	10
X	Special

Performance Criterion: A

Test Procedure

- 1) Let the EUT work in test mode and test it.
- 2) The EUT are placed on an insulating support 0.1 m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3 m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 3) The disturbance signal described below is injected to EUT through CDN.
- 4) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 5) The frequency range is swept from 150 kHz to 80 MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1KHz sine wave.
- 6) The rate of sweep shall not exceed 1.5*10-3decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 7) An artificial ear and sound level meter are used to monitor the sound pressure level. RF communication test set is used to monitor the noise level.
- 8) Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jack Wang on 2010-01-14.

Test Mode: Talking

Table 1: AC mains power input port

Modulation: Amplitude 80%, 1 kHz sine wave

Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

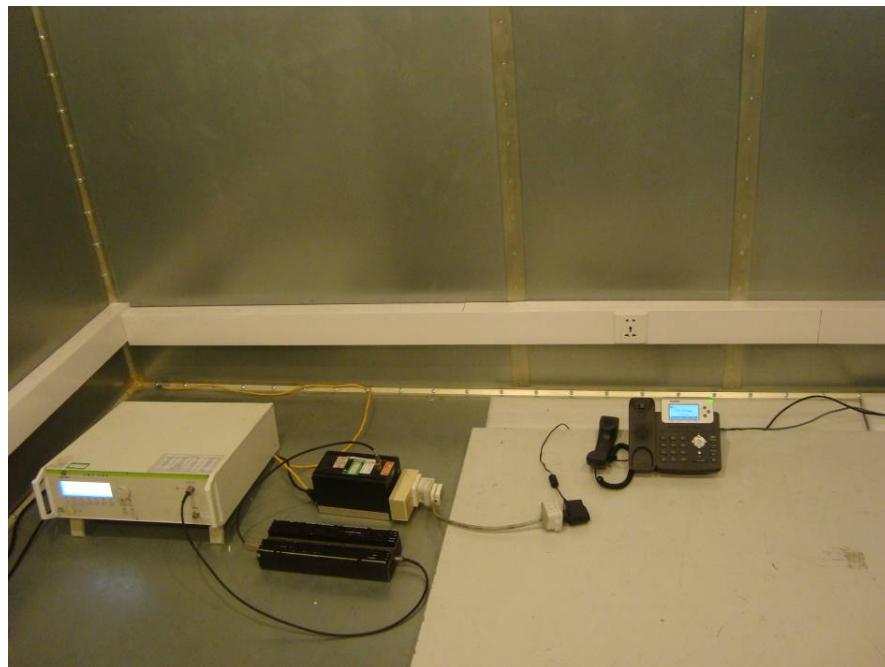
Table 2: RJ45 port

Modulation: Amplitude 80%, 1 kHz sine wave

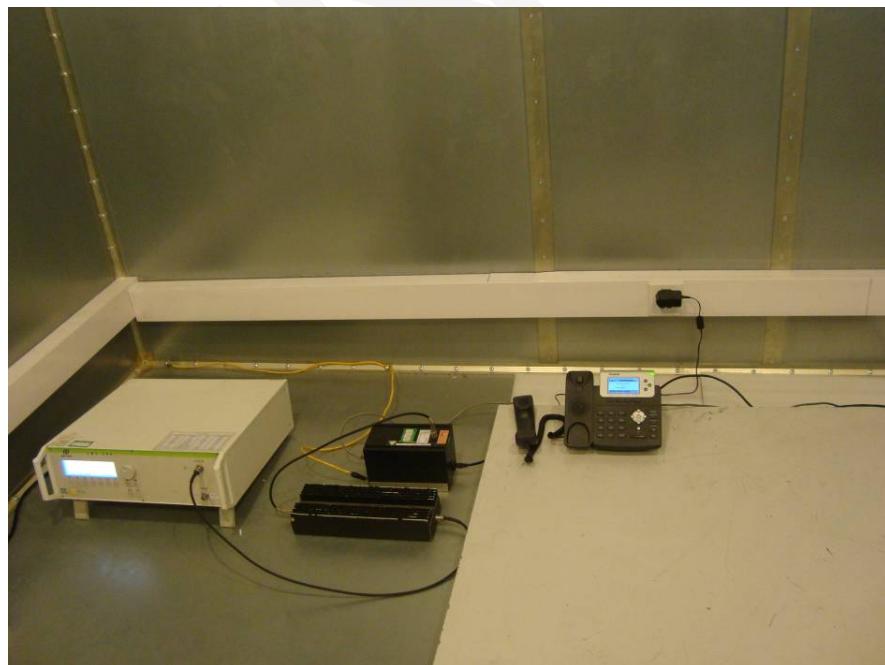
Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

AC Mains



RJ45 Port



Test Setup Photos

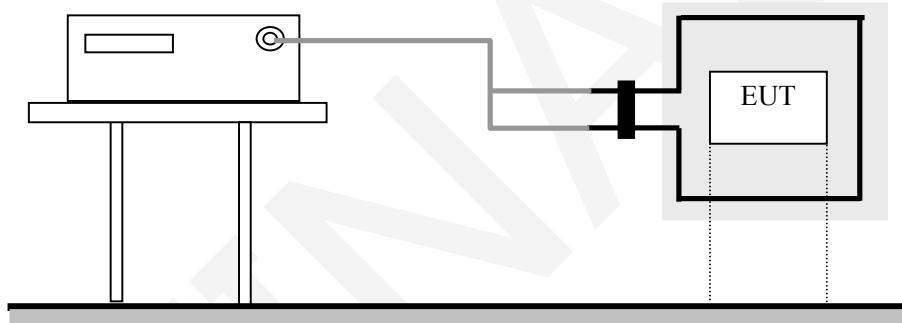
EN 55024 §4.2.4-POWER FREQUENCY MAGNETIC FIELDS (IEC 61000-4-8)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Simulator	UCS 500 N5	V0939105172	2009-10-20	2010-10-20
EM Test	Auto-transformer	MV2616	0403-16	2009-03-25	2010-03-25
EM Test	MC 2630	MC 2630	0309-59	2009-03-07	2010-03-07
EM Test	Loop Antenna	MS100	303298	2009-03-07	2010-03-07

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Setup



Test Standard

EN 55024:2010 (IEC 61000-4-8:2009)
Test level 1 at 1A/m

Test Level

Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
X.	Special

Performance criterion: A

Test Procedure

The EUT shall be subjected to the test magnetic field by using the induction coil of standard dimensions (1 m*1 m). The induction coil shall then be rotated by 90° in order to expose the EUT to the test field with different orientations.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jack Wang on 2010-01-12.

Test Mode: Talking

Level	Magnetic Field Strength A/m	X (Horizontal)	Y (Vertical)	Z (Special)
1	1	A	A	A
2	3	/	/	/
3	10	/	/	/
4	30	/	/	/
5	100	/	/	/
X	Special	/	/	/



Test Setup Photos

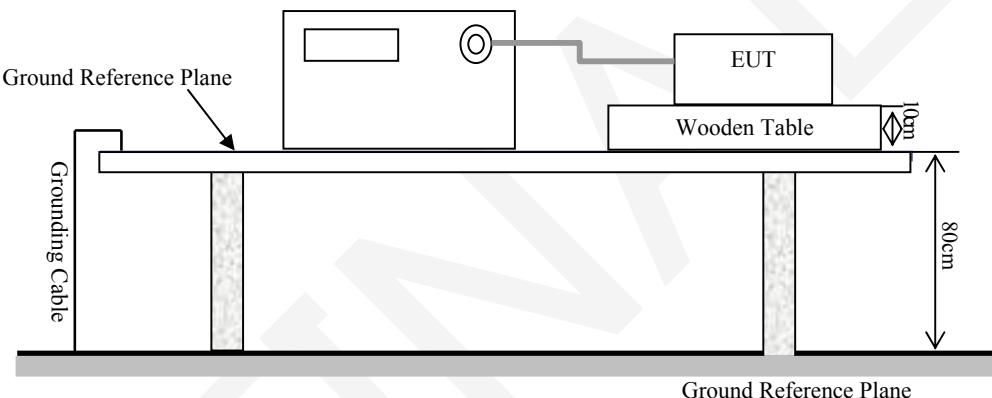
EN 55024 §4.2.5-SURGES (IEC 61000-4-5)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Simulator	UCS 500 N5	V0939105173	2009-10-20	2010-10-20
EM Test	Auto-transformer	MV2616	0403-16	2009-03-25	2010-03-25
EM Test	CNV 504N	CNV 504N	V0939105174	2009-10-16	2010-10-16

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup



Test Standard

EN 55024:2010 (IEC 61000-4-5:2005)

AC Mains: L-N: Test level 2 at 1 kV

Signal port: Test level 2 at 1 kV

Test Level

Level	Open Circuit Output Test Voltage ±10%
1	0.5 kV
2	1 kV
3	2 kV
4	4 kV
X	Special

Performance criterion: B

Test Procedure

- 1) For input a.c. power ports, provide a 1 kV 1.2/50μs voltage surge (at open-circuit condition) and a 8/20 μs current surge into a short circuit.
- 2) For signal ports and telecommunication ports, provide a 0.5 kV 10/700μs voltage surge (at open-circuit condition).
- 3) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are conducted during test.
- 4) Different phase angles are done individually.
- 5) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jack Wang on 2010-01-12.

Test Mode: Talking

Table 1: AC mains power input port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	L-N	A	/
2	1kV	±	L-N	A	/
3	2kV	±	L-PE, N-PE	/	/
4	4kV	±	L-N, L-PE, N-PE	/	/

Table 2: RJ45 port

Level	Voltage	Poll	Path	Pass	Fail
1	0.5kV	±	Line-Ground	A	/
2	1kV	±	Line-Ground	A	/
3	2kV	±	Line-Line, Line-Ground	/	/
4	4kV	±	Line-Line, Line-Ground	/	/

AC mains



RJ45 port



Test Setup Photos

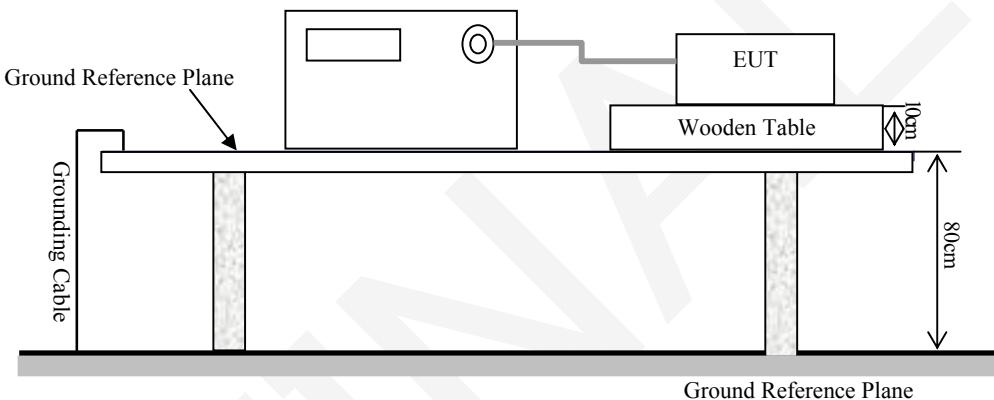
EN 55024 §4.2.6-VOLTAGE DIPS AND INTERRUPTIONS (IEC 61000-4-11)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Simulator	UCS 500 N5	V0939105173	2009-10-20	2010-10-20
EM Test	Auto-transformer	MV2616	0403-16	2009-03-25	2010-03-25

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test Setup



Test Standard

EN 55024:2010 (IEC 61000-4-11:2004)
Test levels and Performance Criterion

Test Level

Test Level	Voltage dip and short interruptions %UT	Duration (Periods)	Performance Criterion
1	>95	0.5	B
2	30	25	C
3	>95	250	C

Test Procedure

- 1) The interruption is introduced at selected phase angles with specified duration.
- 2) Record any degradation of performance.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 °C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Jack Wang on 2010-01-12.

Test Mode: Talking

Level	U2 (% Reduction)	Td(Periods)	Phase Angle	N	Pass	Fail
1	>95%	0.5	0/90/180/270	3	A	/
2	30%	25	0/90/180/270	3	A	/
3	>95%	250	0/90/180/270	3	B	/



Test Setup Photo

EN 61000-3-2-HARMONIC CURRENT EMISSIONS

According to EN 61000-3-2:2006 + A1:2009 + A2:2009 section 7: Equipment with a rated power of 75 W or less, other than discharge lighting equipment, are not included in this standard.

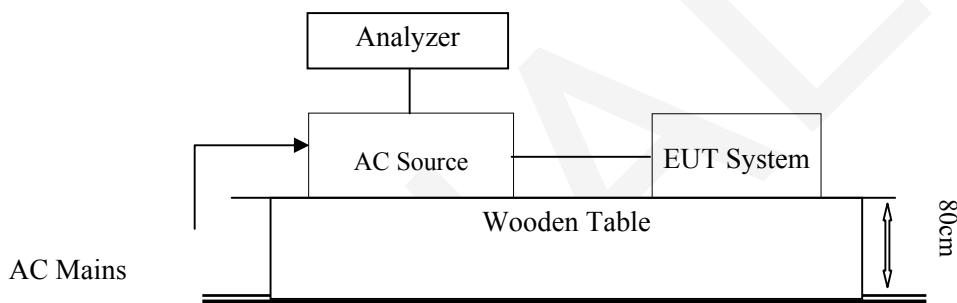
EN 61000-3-3- VOLTAGE FLUCTUATION AND FLICKER

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Harmonic/Flicker Analyzer	DPA 500N	V0939105176	2012-11-24	2013-11-23
EM Test	AC Source	ACS500	303276	2011-04-11	2013-04-10

*** Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to requirements that traceable to National Primary Standards and International System of Units (SI).

Test System Setup



Test Standard

EN 61000-3-3:2008

Flicker Test Limits :

The limits shall be applicable to voltage fluctuations and flicker at the supply terminals of the equipment under test, measured or calculated according to clause 4 under test conditions described in clause 6 and annex A. Tests made to prove compliance with the limits are considered to be type tests.

The following limits apply:

- the value of Pst shall not be greater than 1,0;
- the value of Plt shall not be greater than 0,65;
- the value of d(t) during a voltage change shall not exceed 3,3 % for more than 500 ms;
- the relative steady-state voltage change, dc, shall not exceed 3,3 %;
- the maximum relative voltage change dmax, shall not exceed
 - a) 4 % without additional conditions;
 - b) 6 % for equipment which is:
 - switched manually, or
 - switched automatically more frequently than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds), or manual restart, after a power supply interruption.

Note: The cycling frequency will be further limited by the Pst and Plt limit. For example: a dmax of 6 % producing a rectangular voltage change characteristic twice per hour will give a Plt of about 0,65.

c) 7 % for equipment which is

- attended whilst in use (for example: hair dryers, vacuum cleaners, kitchen equipment such as mixers, garden equipment such as lawn mowers, portable tools such as electric drills), or
- switched on automatically, or is intended to be switched on manually, no more than twice per day, and also has either a delayed restart (the delay being not less than a few tens of seconds) or manual restart, after a power supply interruption.

In the case of equipment having several separately controlled circuits in accordance with 6.6, limits b) and c) shall apply only if there is delayed or manual restart after a power supply interruption; for all equipment with automatic switching which is energized immediately on restoration of supply after a power supply interruption, limits a) shall apply; for all equipment with manual switching, limits b) or c) shall apply depending on the rate of switching. Pst and Plt requirements shall not be applied to voltage changes caused by manual switching. The limits shall not be applied to voltage changes associated with emergency switching or emergency interruptions.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25°C
Relative Humidity:	50 %
ATM Pressure:	100.0 kPa

Date of test:	16:03 12 Jul. 2013
Tester:	Joson Xiao
Standard used:	EN/IEC 61000-3-3 Flicker
Short time (Pst):	10 min
Observation time:	120 min (12 Flicker measurements)
Flicker meter:	230V / 50Hz
Customer:	YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.
E. U. T.:	IP PHONE
Model:	SIP-T22P
Test Mode:	Talking (adapter 2 power supply)

Maximum Flicker results

	EUT values	Limit	Result
Pst	0.028	1.00	Pass
Plt	0.028	0.65	Pass
dc [%]	0.015	3.30	Pass
dmax [%]	0.274	4.00	Pass
dt [s]	0.000	0.50	Pass

**Test Setup Photo**

Date of test:	16:29 12 Jul. 2013
Tester:	Joson Xiao
Standard used:	EN/IEC 61000-3-3 Flicker
Short time (Pst):	10 min
Observation time:	120 min (12 Flicker measurements)
Flicker meter:	230V / 50Hz
Customer:	YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.
E. U. T.:	IP PHONE
Model:	SIP-T22P
Test Mode:	Talking (adapter 3 power supply)

Maximum Flicker results

	EUT values	Limit	Result
Pst	0.028	1.00	Pass
Plt	0.028	0.65	Pass
dc [%]	0.015	3.30	Pass
dmax [%]	0.056	4.00	Pass
dt [s]	0.000	0.50	Pass



Test Setup Photo

Date of test:	16:56 12 Jul. 2013
Tester:	Joson Xiao
Standard used:	EN/IEC 61000-3-3 Flicker
Short time (Pst):	10 min
Observation time:	120 min (12 Flicker measurements)
Flicker meter:	230V / 50Hz
Customer:	YEALINK (XIAMEN) NETWORK TECHNOLOGY CO., LTD.
E. U. T.:	IP PHONE
Model:	SIP-T22P
Test Mode:	Talking (PoE power supply)

Maximum Flicker results

	EUT values	Limit	Result
Pst	0.037	1.00	Pass
Plt	0.029	0.65	Pass
dc [%]	0.016	3.30	Pass
dmax [%]	0.282	4.00	Pass
dt [s]	0.000	0.50	Pass



Test Setup Photo

EXHIBIT A - PRODUCT LABELING**Label Specification**

Specifications: The marking set out above must be affixed to the apparatus or to its data plate and have a minimum height of 5 mm. The elements should be easily readable and indelible. They may be placed anywhere on the apparatus case or in its battery compartment. No tool should be needed to view the marking.

Label Location on EUT

EXHIBIT B - EUT PHOTOGRAPHS

EUT – All View



EUT – Top View



EUT – Bottom View



EUT – Front View



EUT – Rear View



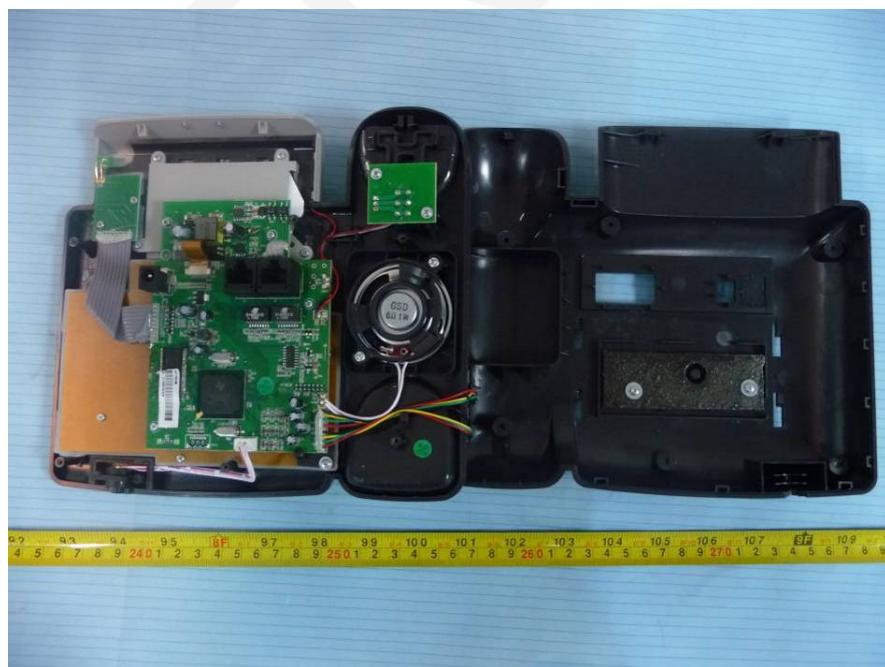
EUT – Left View



EUT – Right View



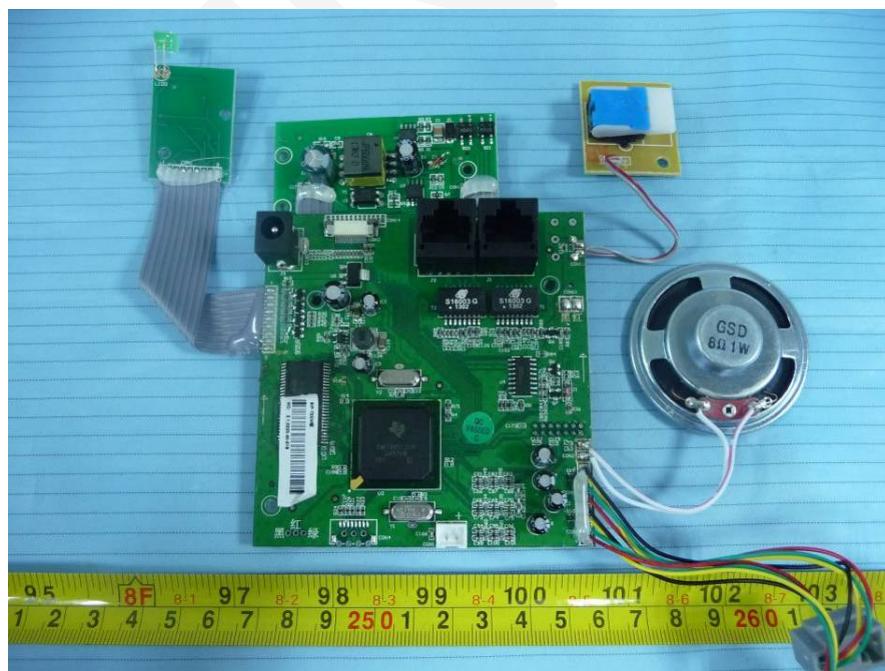
EUT – Base Cover off View



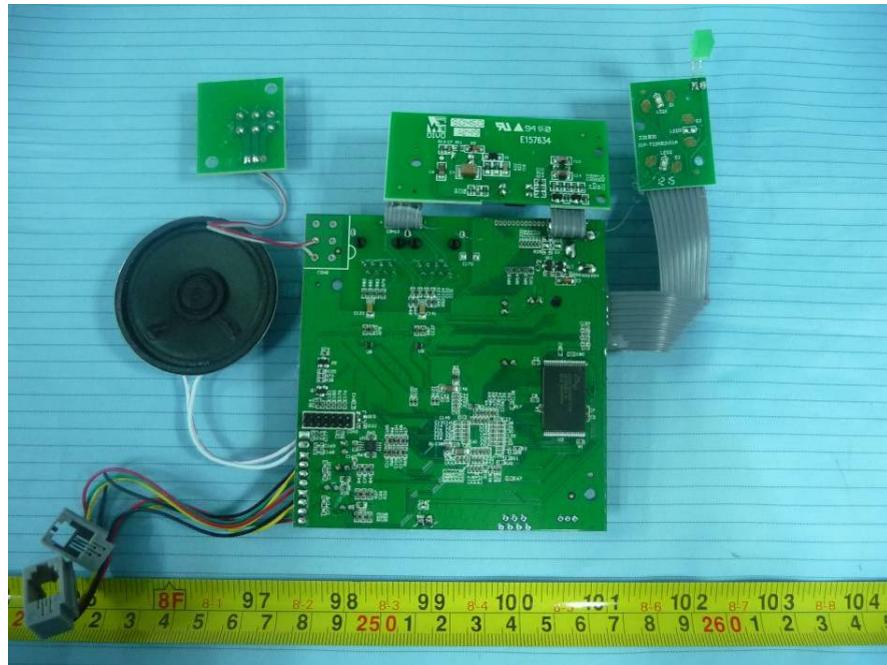
EUT – Handset Cover off View



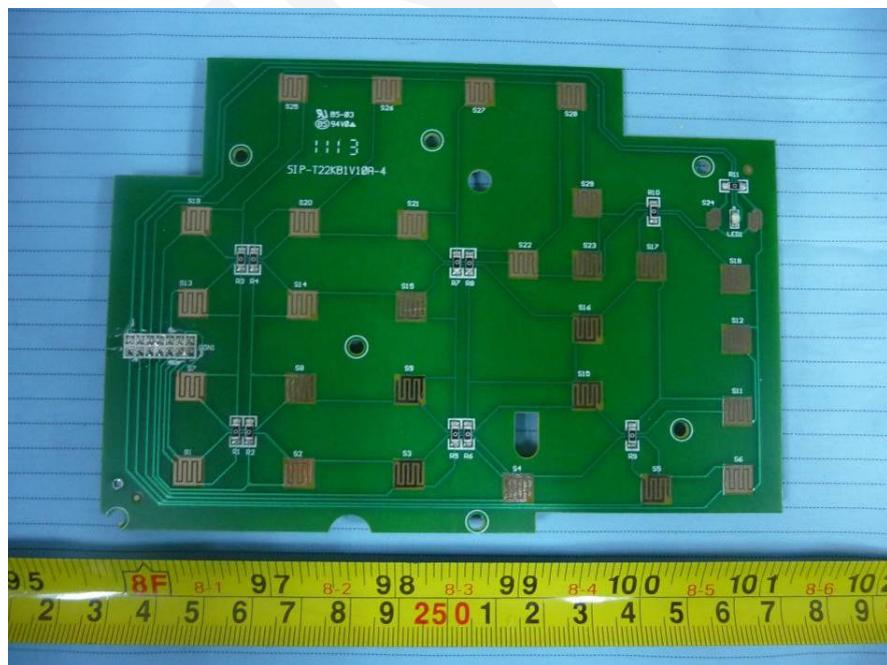
EUT – Main Board Top View



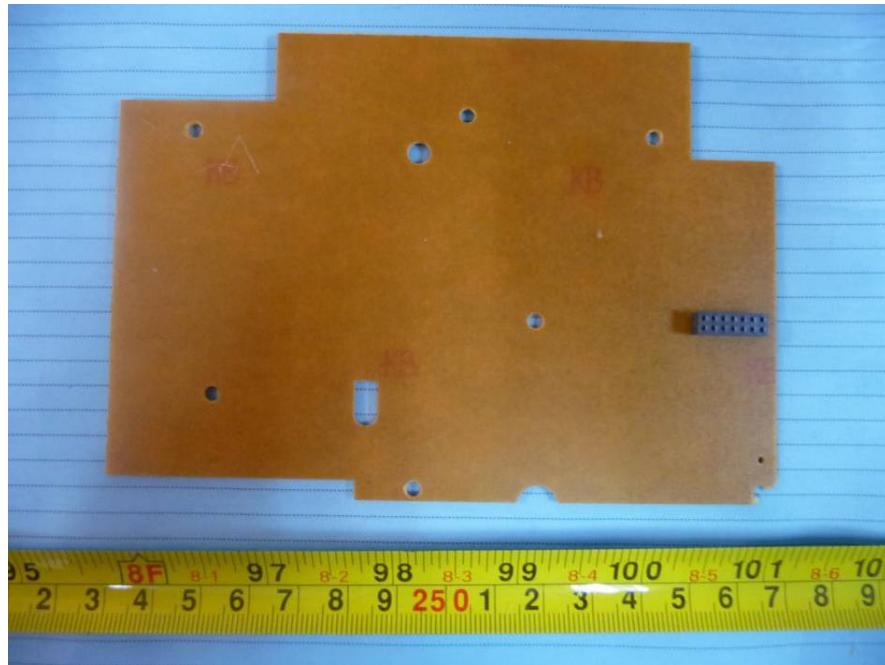
EUT – Main Board Bottom View



EUT – Key Board Top View



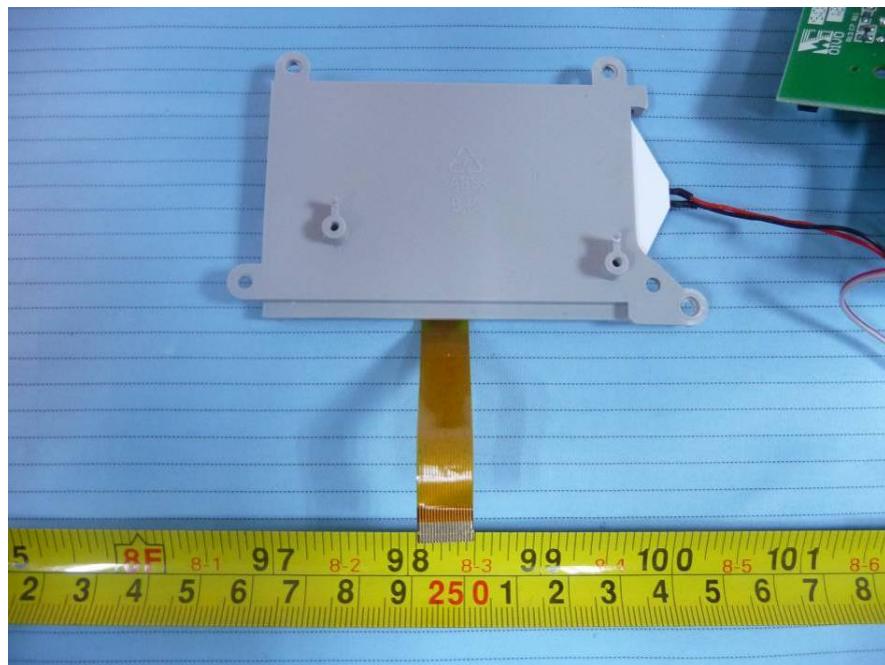
EUT – Key Board Bottom View



EUT – LCD Screen Top View



EUT – LCD Screen Bottom View



EUT – Adapter 1 Label View



EUT – Adapter 2 Label View



EUT – Adapter 3 Label View



EXHIBIT C - TEST SETUP PHOTOGRAPHS

Conducted Disturbance - Front View (Adapter power supply)



Conducted Disturbance - Side View (Adapter power supply)



Conducted Disturbance - Front View (PoE power supply)



Conducted Disturbance - Side View (PoE power supply)



Conducted Disturbance - Front View (RJ45 Port)



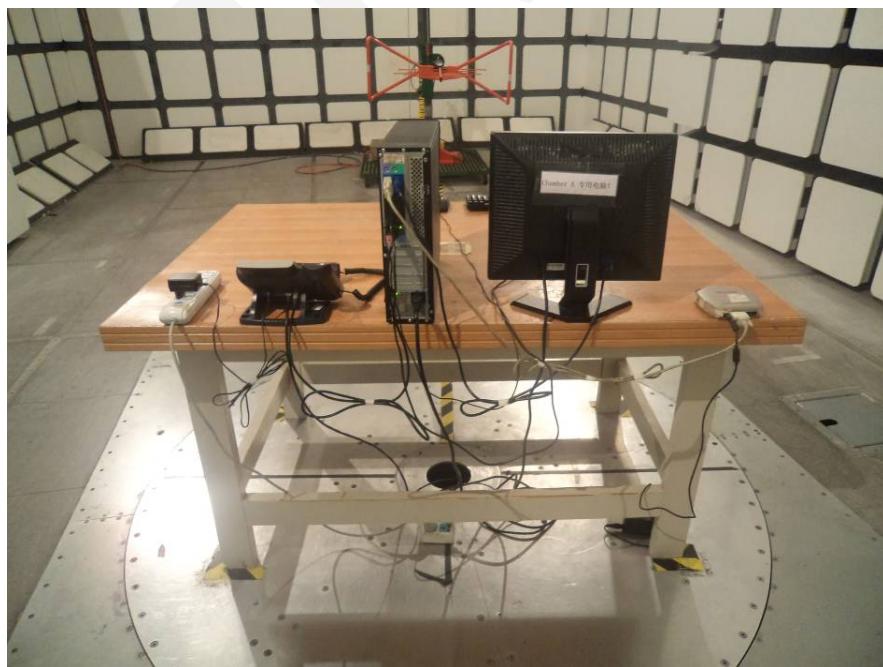
Conducted Disturbance - Side View (RJ45 Port)



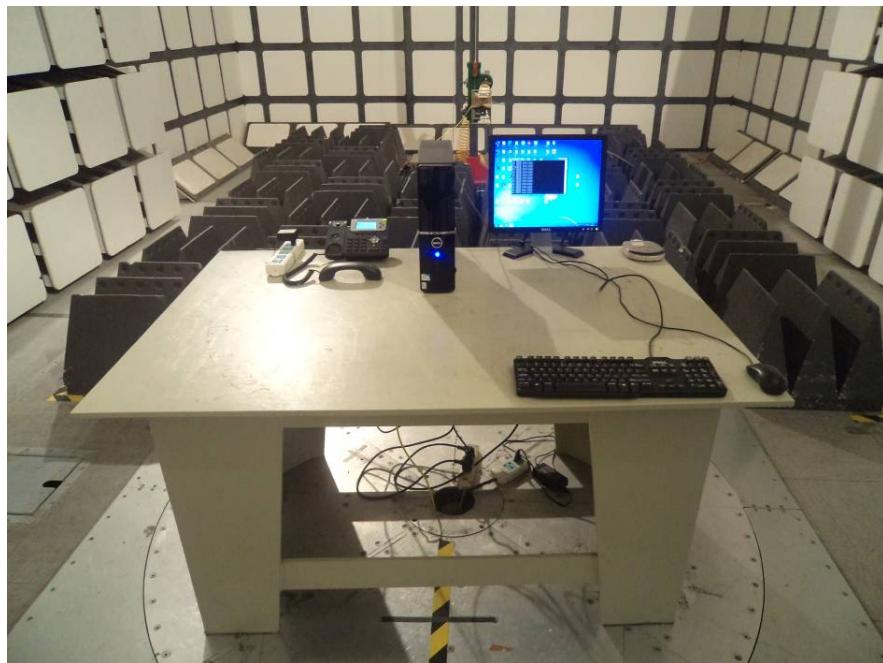
Below 1 GHz: Radiated Disturbance - Front View (Adapter power supply)



Below 1 GHz: Radiated Disturbance - Rear View (Adapter power supply)



Above 1 GHz: Radiated Disturbance - Front View (Adapter power supply)



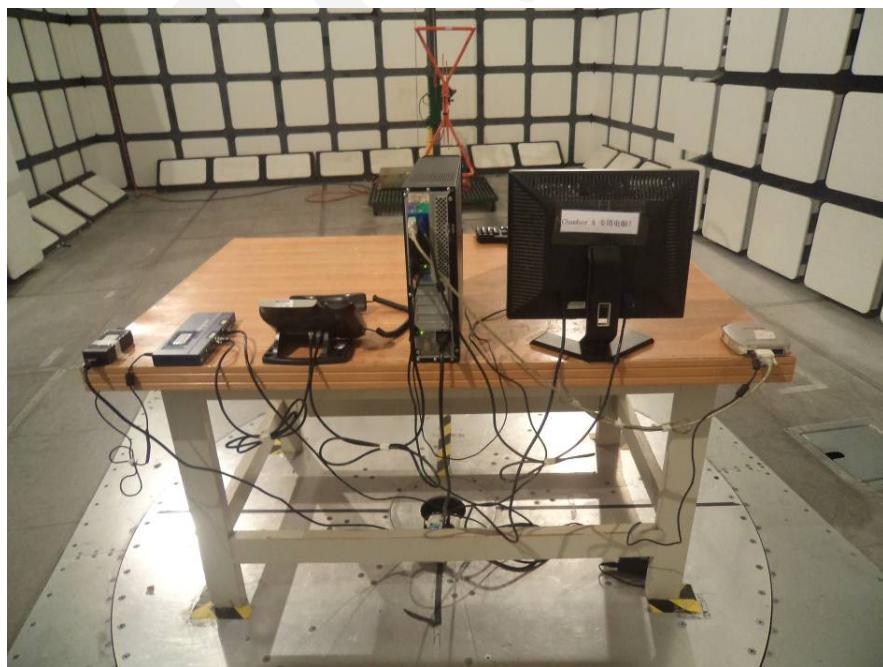
Above 1 GHz: Radiated Disturbance - Rear View (Adapter power supply)



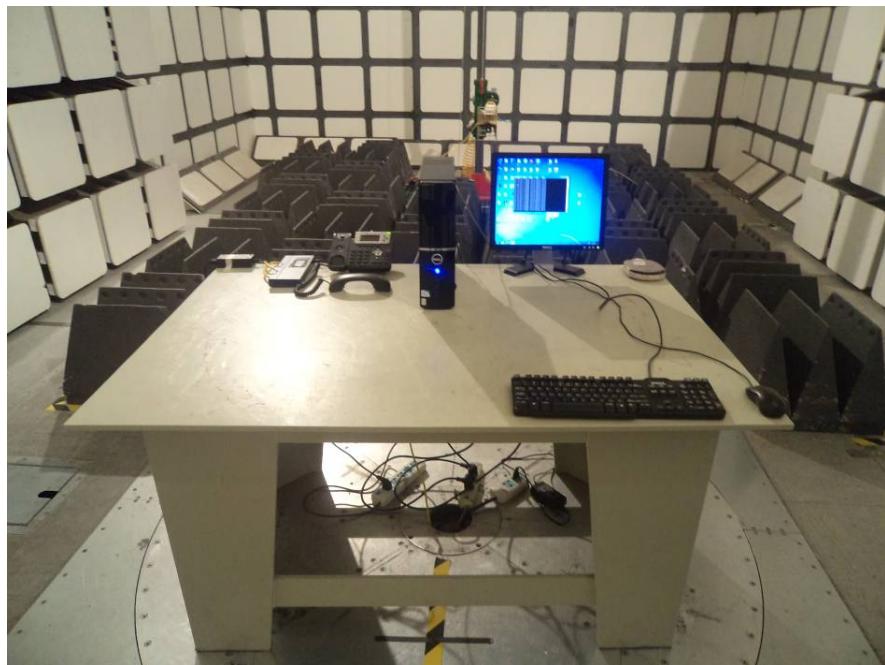
Below 1 GHz: Radiated Disturbance - Front View (PoE power supply)



Below 1 GHz: Radiated Disturbance - Rear View (PoE power supply)



Above 1 GHz: Radiated Disturbance - Front View (PoE power supply)



Above 1 GHz: Radiated Disturbance - Rear View (PoE power supply)



PRODUCT SIMILARITY DECLARATION LETTER



Yealink (Xiamen) Network Technology Co., LTD

4th-5th Floor, South Building, NO.63 WangHai Road, 2nd Software Park, Xiamen, China

Tel: 86-592-5702000 Fax: 86-592-5702455

2013-6-21

Product Similarity Declaration Letter

To Whom It May Concern,

We, Yealink (Xiamen) Network Technology Co., LTD. hereby declare that our product IP Phone, the model SIP-T22P and SIP-T22 are electrically identical, they have the same PCB layout and schematic, the only difference is the model SIP-T22P with POE circuit, the model SIP-T22 without POE circuit . SIP-T22P was tested by BACL.

Please contact me if you have any question.

Signature:

A handwritten signature in black ink, appearing to read "Stone Lu".

Stone Lu

Vice General Manager

******* END OF REPORT *******